The Abdus Salam International Centre for Theoretical Physics

2359-10

Joint ICTP-IAEA Workshop on Physics of Radiation Effect and its Simulation for Non-Metallic Condensed Matter

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Modeling of damage in ion irradiated semiconductors

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Modeling of damage in ion irradiated semiconductors

Radiation damage is the general alteration of the operational properties of a semiconductor devices induced by ionizing radiation

Three main types of effects:

- Transient ionization. This effect produces electron-hole pairs; particle detection with semiconductors is based on this effect.

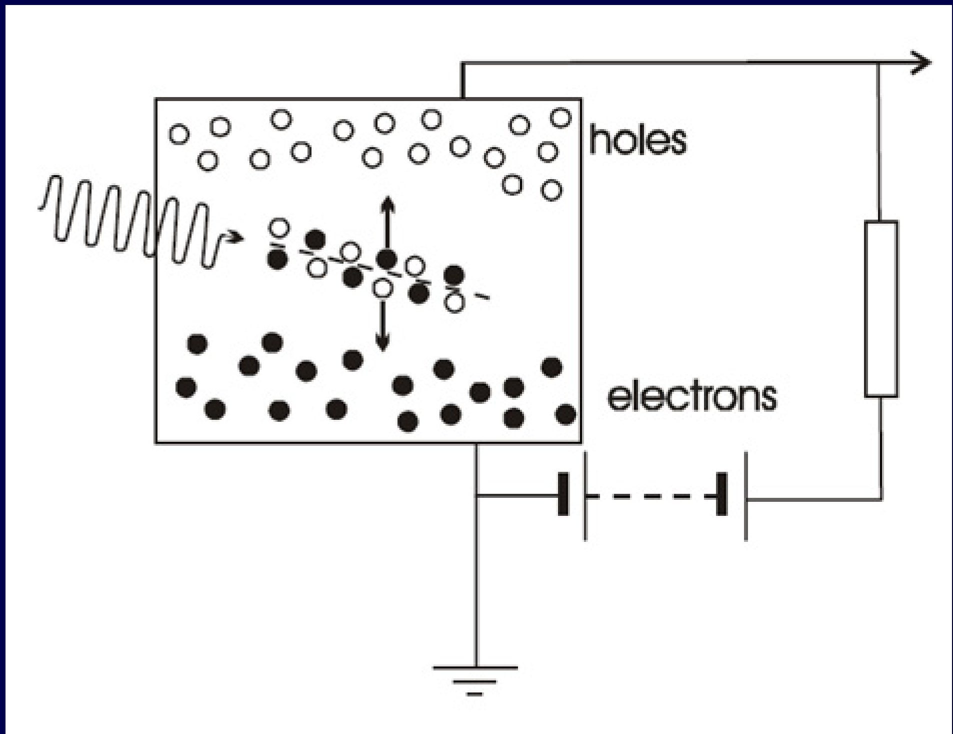
-Long term ionization. In insulators, the material does not return to its initial state, if the electrons and holes produced are fixed, and charged regions are induced.

- Displacements. These are dislocations of atoms from their normal sites in the lattice, producing less ordered structures, with long term effects on semiconductor properties.

V.A.J. van Lint, The physics of radiation damage in particle detectors, Nucl. Instrum. Meth. A253 (1987) 453.

Transient ionization.

This effect produces electron-hole pairs; particle detection with semiconductors is based on this effect. (IBIC)



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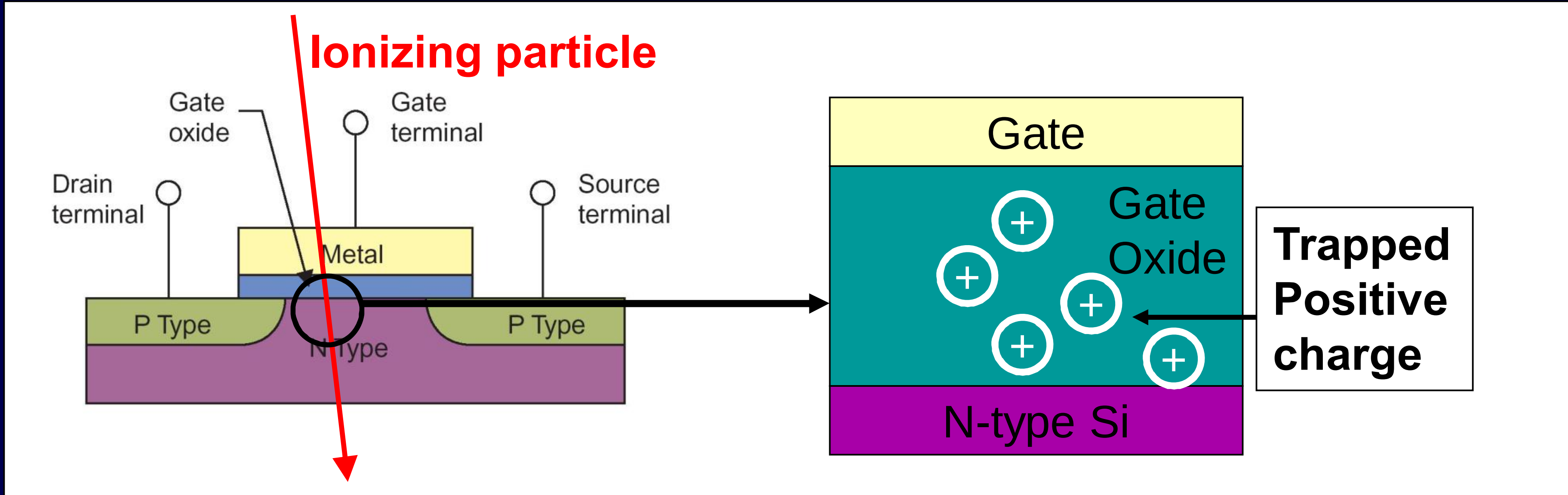


- **Parametric shifts** in transistors parameters due to the build-up of trapped positive charge and interface states caused by several low-LET particles striking a chip
- Total Ionizing Dose affects **dielectric layers** (e.g., gate oxide, isolation oxides)

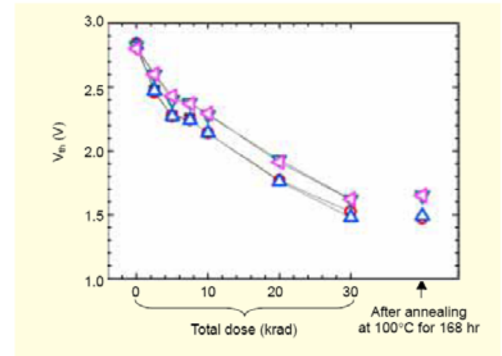


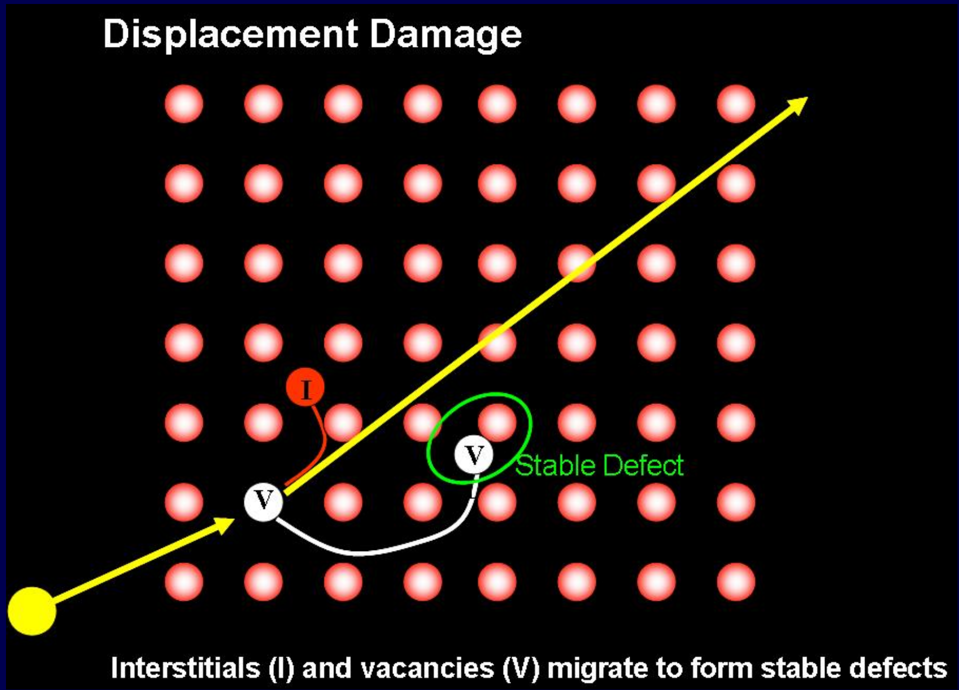
Fig. 1. Threshold voltage (V_{th}) characteristics of a MOSFET (200 V) under a dose rate of 9.55 rad/s.

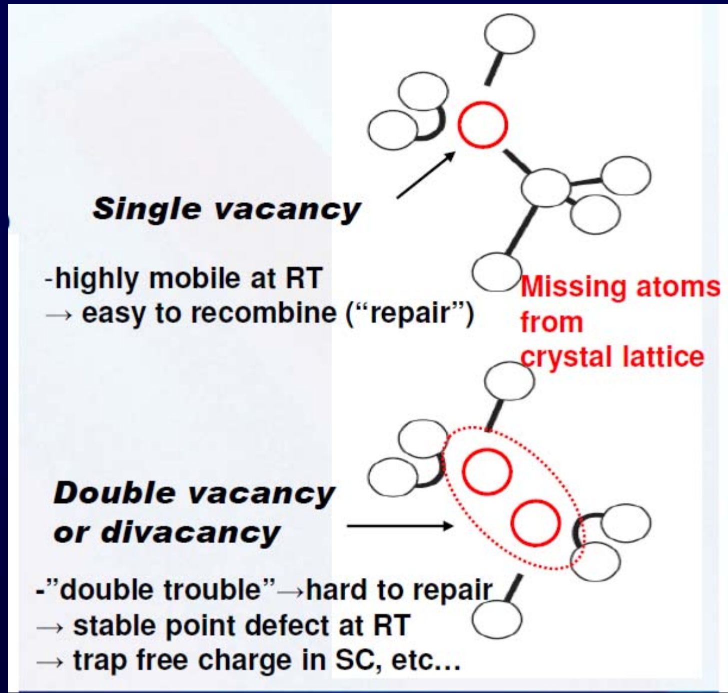
Young Hwan Lho, Ki Yup Kim
Radiation Effects on the Power MOSFET for space applications

http://etrij.etri.re.kr/Cyber/Download/PublishedPaper/2704/S27-04-14.pdf

G. Vizkelethy, "*radiation effects in microelectronic devices*", Thursday 9-10.30

- Displacements. These are dislocations of atoms from their normal sites in the lattice, producing less ordered structures, with long term effects on semiconductor properties





PHYSICAL REVIEW VOLUME 138, NUMBER 2A 19 APRIL 1965

Defects in Irradiated Silicon: Electron Paramagnetic Resonance of the Divacancy

G. D. WATKINS AND J. W. CORBETT

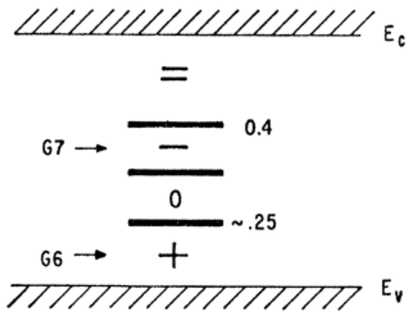
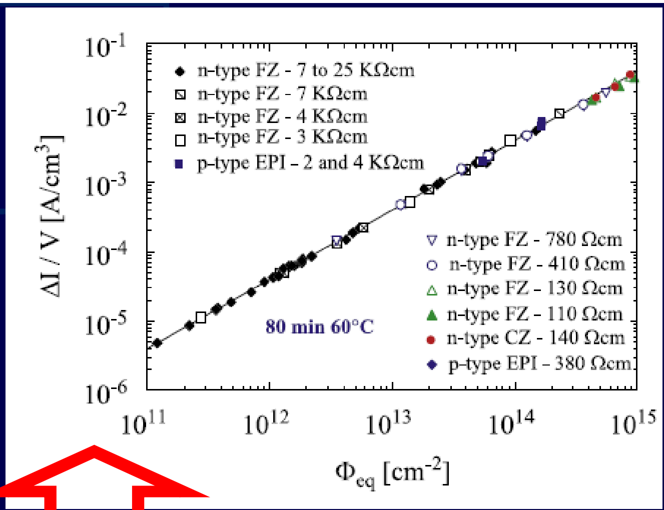
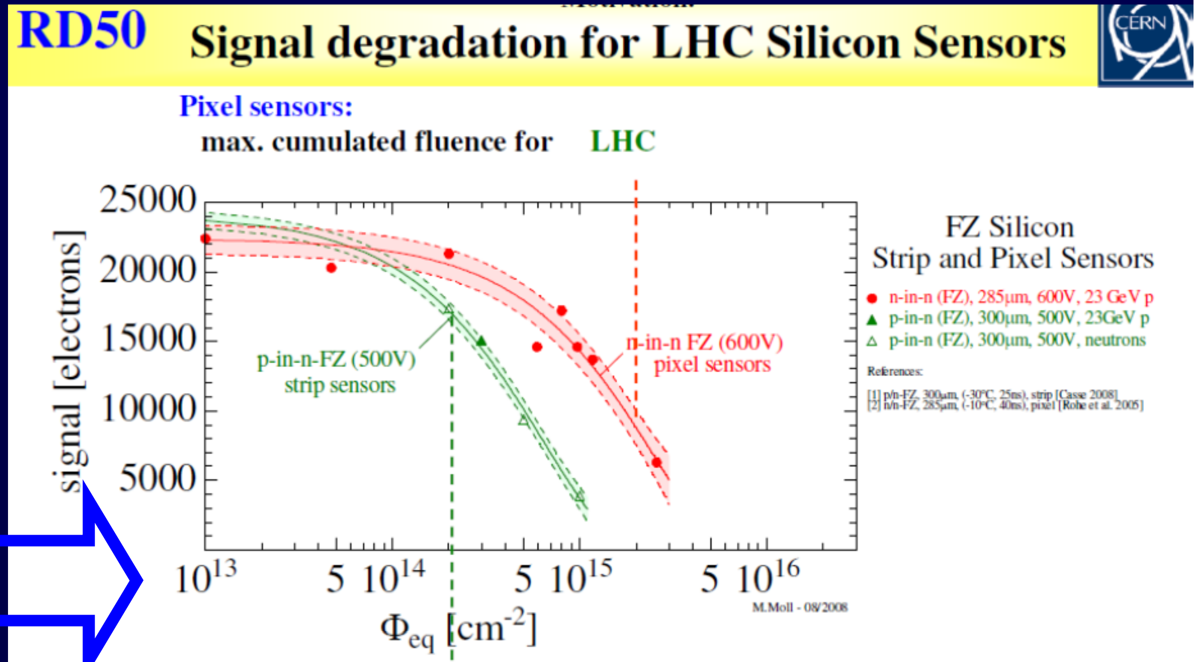


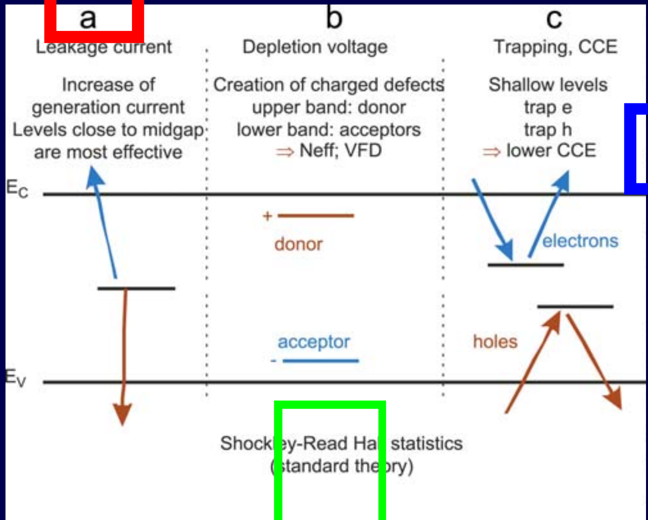
FIG. 14. Electrical levels associated with the divacancy. The level positions (in eV) are given to the nearest band edge. The charge states giving rise to the G6 and G7 spectra are indicated.

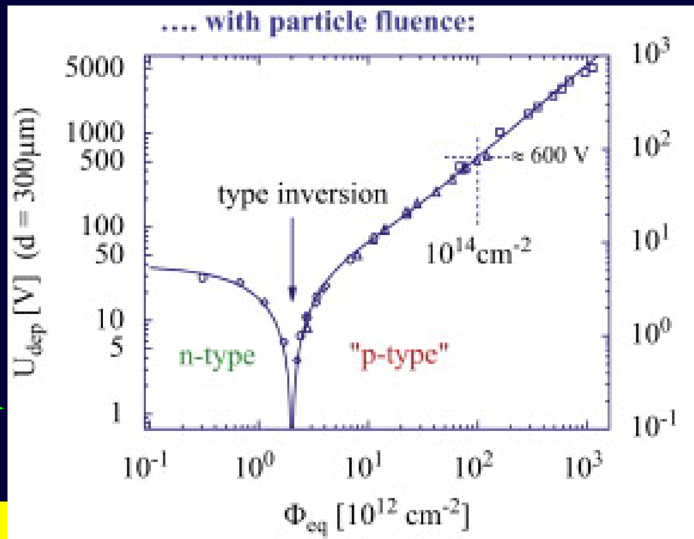
http://holbert.faculty.asu.edu/eee560/RadiationEffectsDamage.pdf

M. Bruzzi, M. Moll, RD50, 2010
http://indico.cern.ch/getFile.py/access?contribId=9&sessionId=2&resId=1&materialId=slides&confId=81149









Frank Hartmann, Silicon tracking detectors in high-energy physics
Nuclear Instruments and Methods in Physics Research A 666 (2012) 25–46

Shockley-Read-Hall Model

Applet Recombination

Excess carrier lifetime

$$\tau = \frac{1}{N_{trap} \cdot \sigma \cdot v_{th}}$$

Trap density

Capture cross section

Thermal velocity

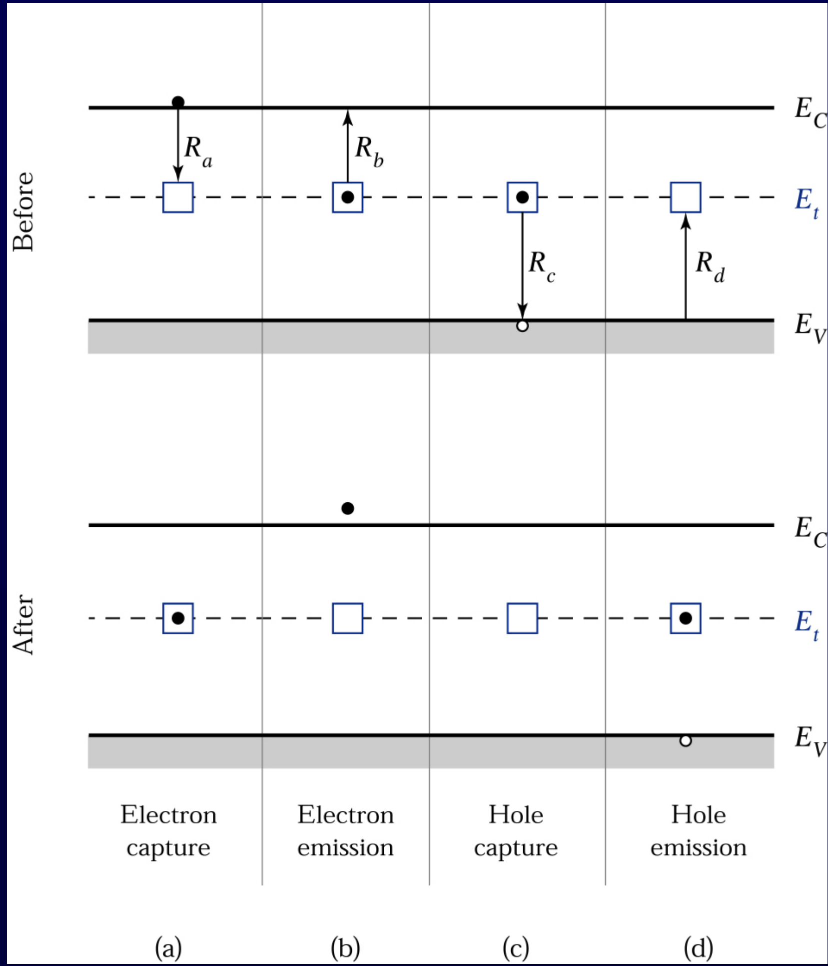


Figure 3.12.
Indirect generation-recombination processes

$$\tau = \frac{1}{N_{trap} \cdot \sigma \cdot v_{th}}$$

Trap density in pristine material

$$N_{trap} = N^0_{trap} + k \cdot \Phi$$

Trap density induced by radiation

$$\frac{1}{\tau(\Phi)} = \frac{1}{\tau_0} + K \cdot \Phi$$

Modeling radiation degradation in solar cells extends satellite lifetime

Robert J. Walters, Scott Messenger, Cory Cress, Maria Gonzalez and Serguei Maximenko

A physics-based model of the effect of radiation on the performance of solar cells in space may enhance the on-orbit lifetime of Earth-orbiting spacecraft.

3 January 2011, SPIE Newsroom. DOI: 10.1117/2.1201012.003417

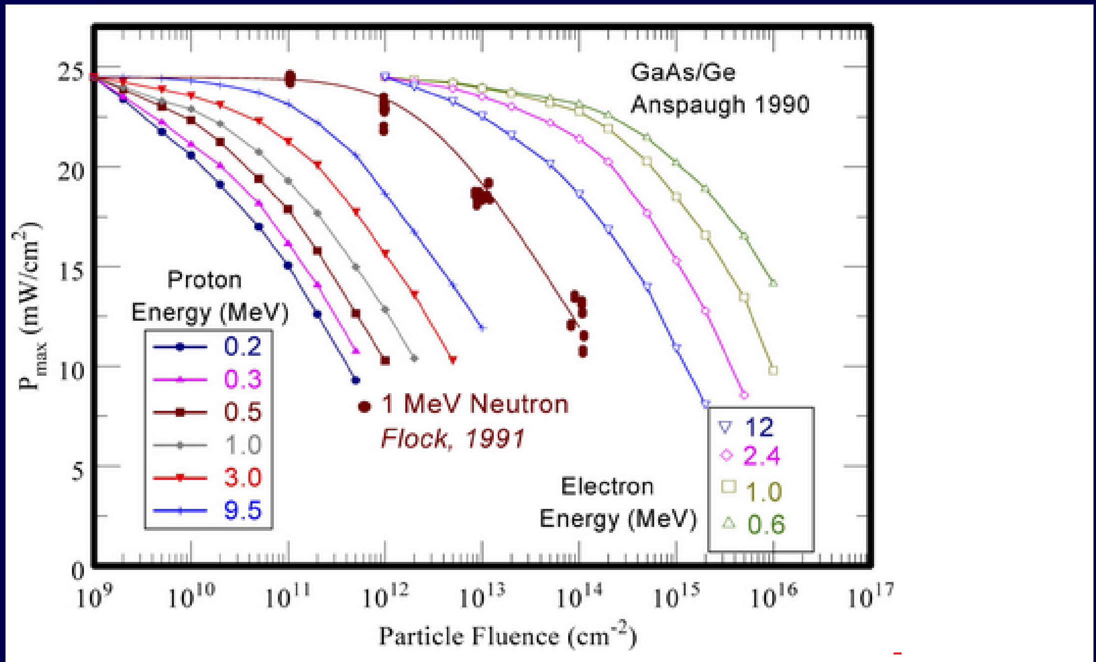


Figure 2. *Measured degradation of a single junction gallium arsenide (GaAs) solar cell under proton, electron,[2] and neutron irradiation.[3] These data can be used to empirically determine the energy dependence of the solar-cell degradation thereby enabling on-orbit performance prediction. P_{max}: Maximum power.*

Space environment-> wide spectrum of ions (protons) and electrons.

To understand the performance of a solar cell in the space radiation environment, it is necessary to know how cell degradation depends on the energy of the irradiating particle.

http://spie.org/x43655.xml

NIEL hypothesis:

the radiation damage is linear proportional to the non-ionizing energy loss of the penetrating particles (radiation) and this energy loss is again linear proportional to the energy used to dislocate lattice atoms (displacement energy).

Final concentration of defects depends only on NIEL and not on the type an initial energy of the particle.

Number of displacements (I-V pairs) is proportional to PKA energy (Kinchin-Pease: N=T/2TD; T: PKA energy; TD: threshold energy to create a Frenkel pair).

Displacement damage dose:

$$D_d = \int \mathrm{NIEL}(E) \cdot \frac{d\Phi}{dE} dE$$

UNITS:

NIEL:(Energy per unit length)/(material density):keV·cm2/g

(in high energy physics the displacement damage cross section (D) in MeV·mb is usually used)

Dd : Energy per unit mass:keV/g

(G.P. Summers et al., IEEE Trans. Nucl. Sci., Vol. 40, pp. 1372, 1993)

How to calculate NIEL from SRIM

10 MeV H+ in Si 100 μm thick

1. Run SRIM and evalutate the total number of vacancy/ion W
2. Evaluate the energy required to create a vacancy M using the modified Kinchin-Pease relationship: the term 2 is due to the binding energy loss that SRIM assign to each vacancy
   Ed is the displacement energy
3. L is the device length and ρ is the mass density

W=4.7 Vac/ion/μm

Ed=20 eV
M=52 eV/vac

$$M = \left(\frac{E_d}{0.8} + 2 \right) eV$$

ρ =2.3 g/cm^3
L=100 μm

$$NIEL = \frac{M \cdot Vac_{Tot}}{\rho \cdot R}$$

S. R. Messenger et al., ***Using SRIM to Calculate the Relative Damage Coefficients for Solar Cells*****, Prog. Photovolt: Res. Appl. 2005; 13:115–123**

If Y is the physical observable (e.g. conductivity, maximum output power for solar cells, Charge Collection Efficiency (CCE) in radiation detectors), which characterizes a tested device subjected to radiation damage, its degradation can be modelled by the following phenomenological relationship:

Device characteristic after irradiation

$$\eta = \frac{Y}{Y_0} = 1 - K \cdot \Phi = 1 - K_{ed} \cdot D_d$$

Device characteristic before irradiation

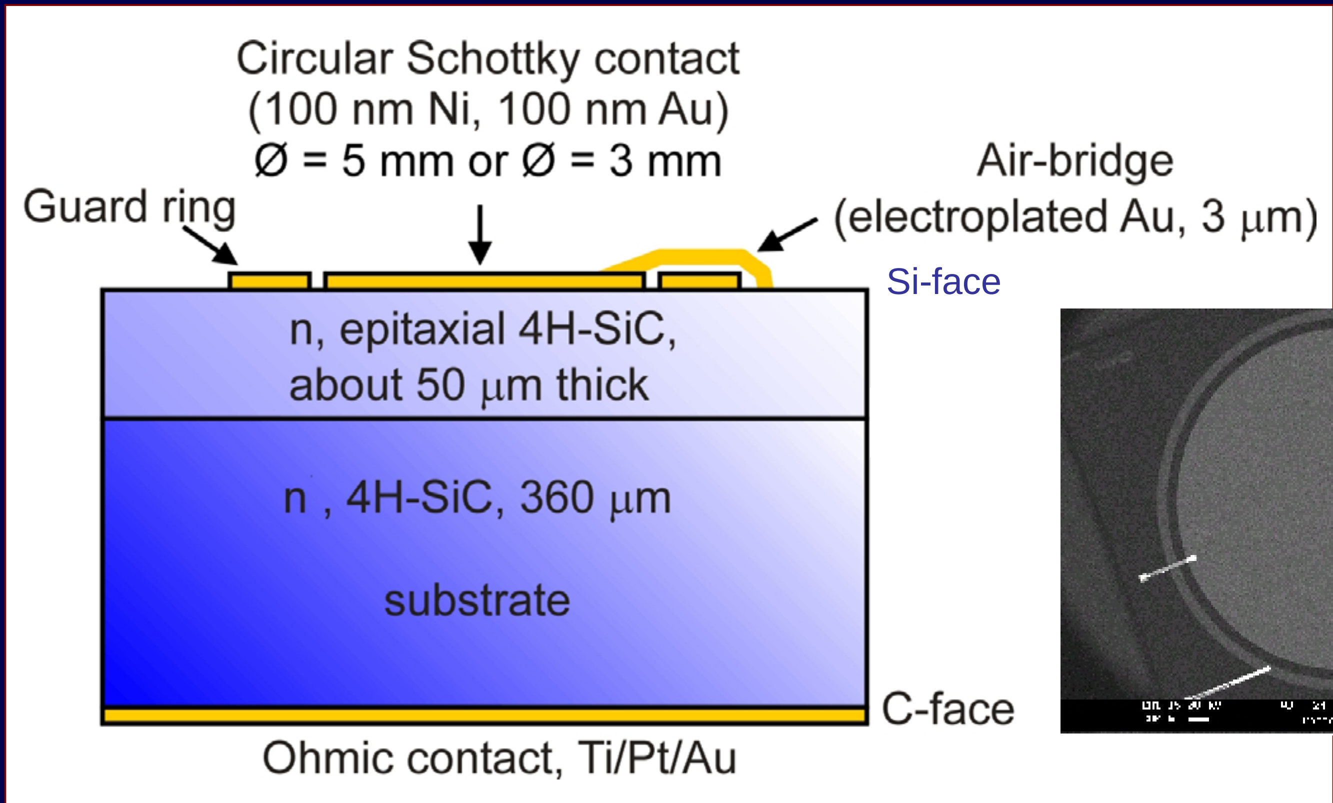
Particle Fluence

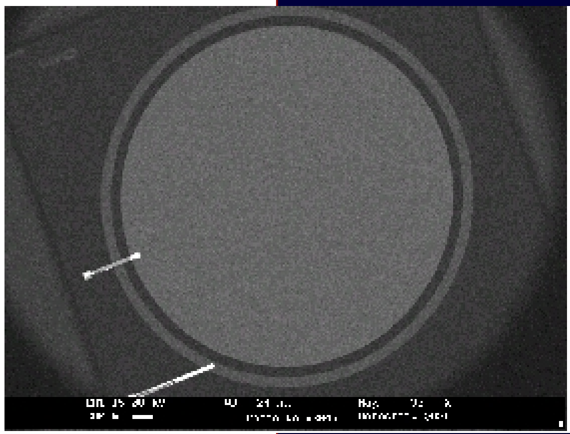
Equivalent damage factor

Displacement dose

Samples

Starting Material: 360 μm n-type 4H-SiC by CREE (USA)
Epitaxial layer from Institute of Crystal Growth (IKZ), Berlin, Germany
Devices from Alenia Marconi System





EXPERIMENTAL PROCEDURE:

Nuclear microprobe facility @ Ruđer Bošković Institute (Zagreb)

Irradiation of an area of 5400 μm^2 by 2 MeV and 1.5 MeV protons.

Final Fluence:

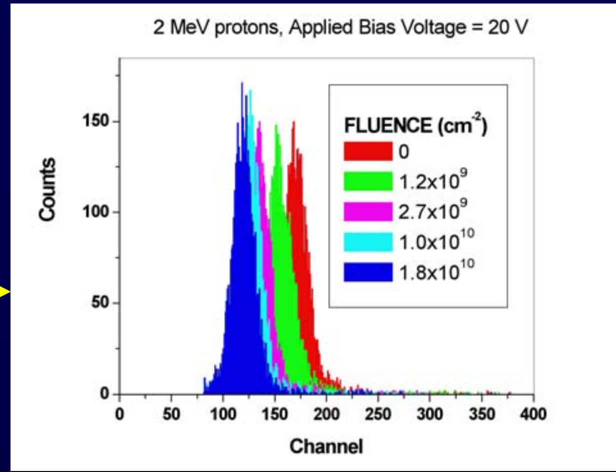
$1.2x10^6$ protons/ $(68x79)\mu m^2 \approx 2x10^{10}$ protons/cm^2

Applied bias voltage = 20 V, 40 V,60 V,...120 V

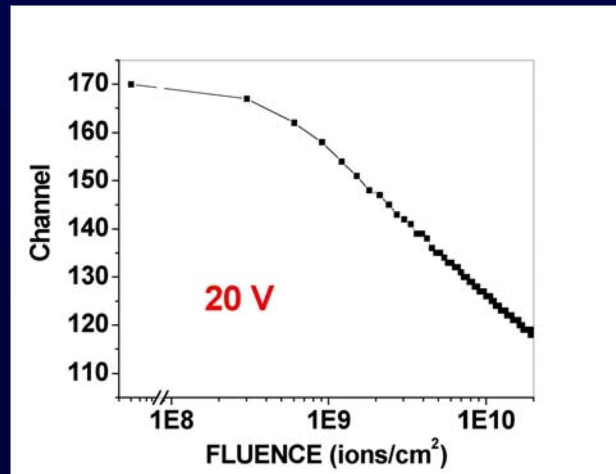
Event by event data acquisition mode.

OFF LINE ANALYSIS

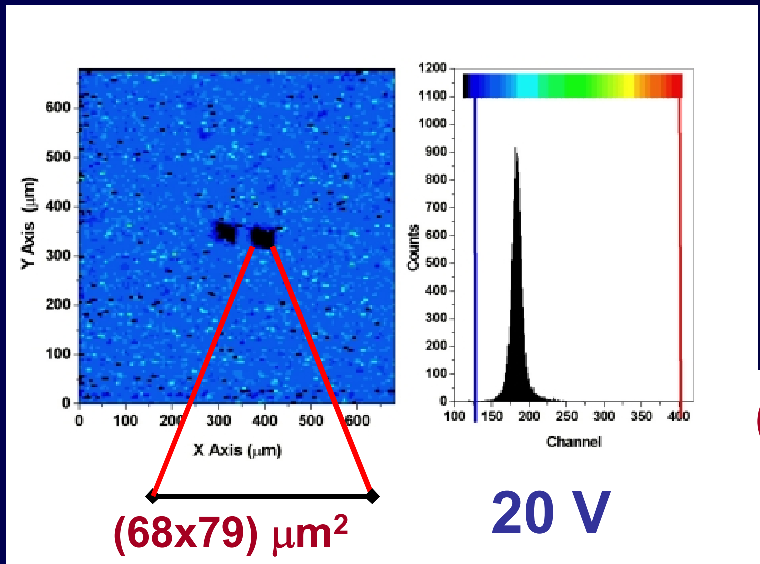
For each scan (about 10^8 ions/cm^2), pulse height spectra are recorded



The median pulse height is evaluated as a function of ion fluence



CONTROL

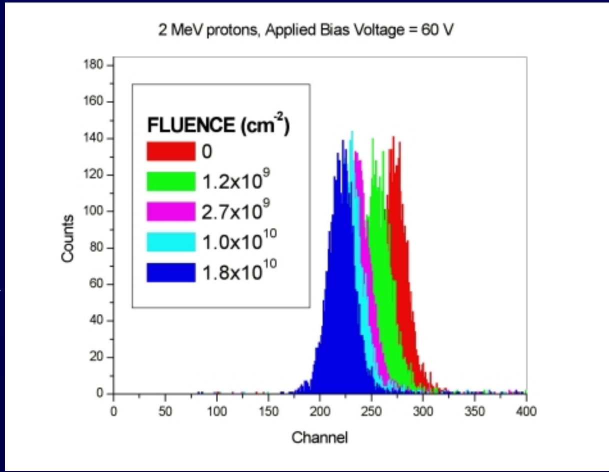


(650x650) μm^2

IBIC map

OFF LINE ANALYSIS

For each scan (about 10^8 ions/cm^2), pulse height spectra are recorded



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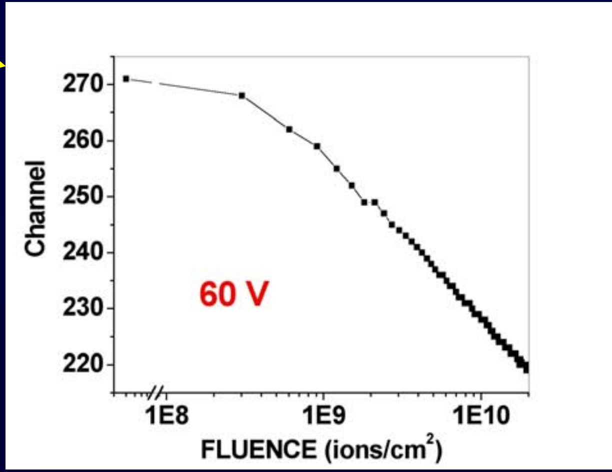

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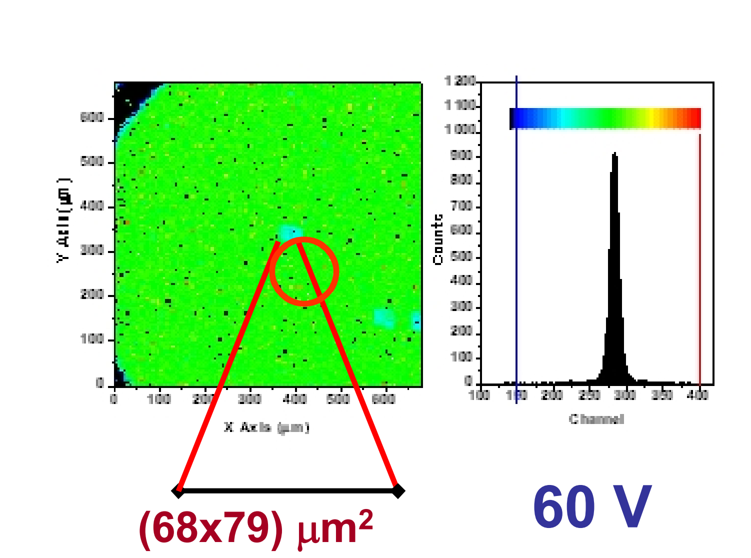
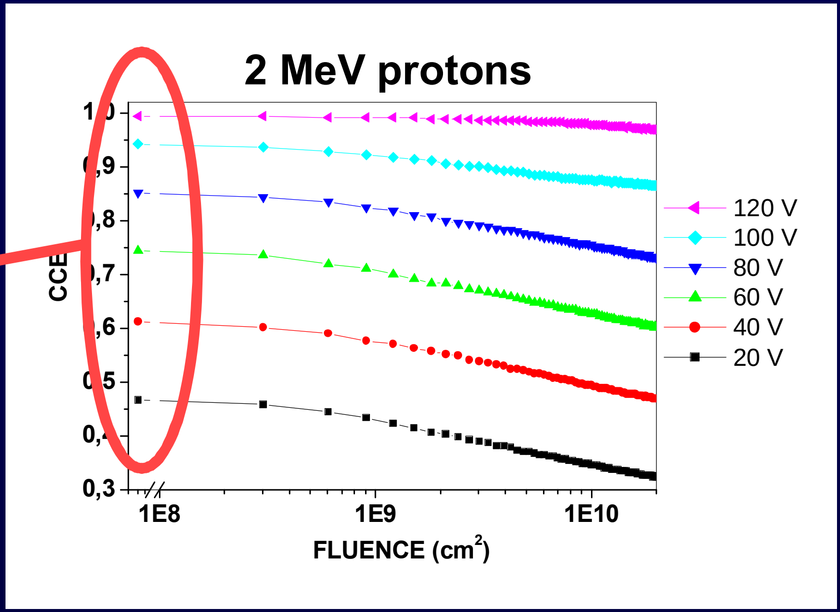


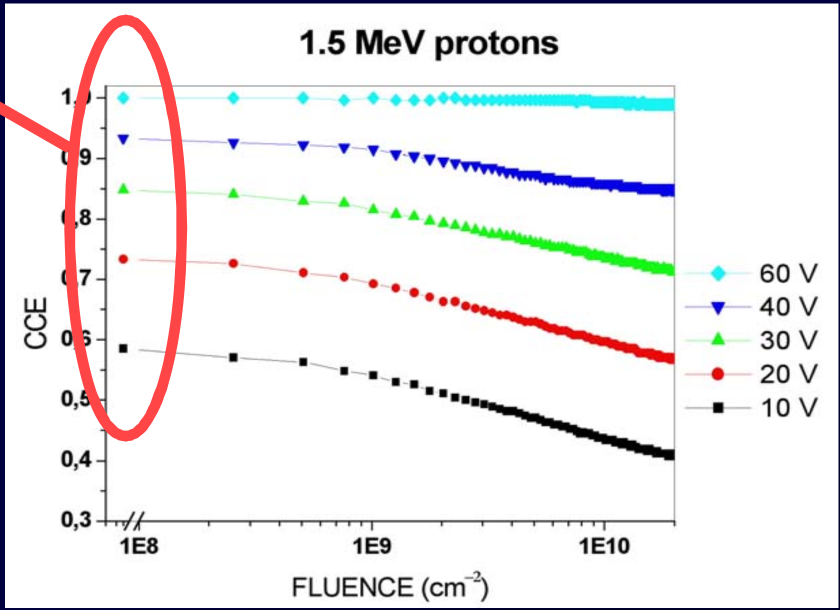
(650x650) µm^2

IBIC map

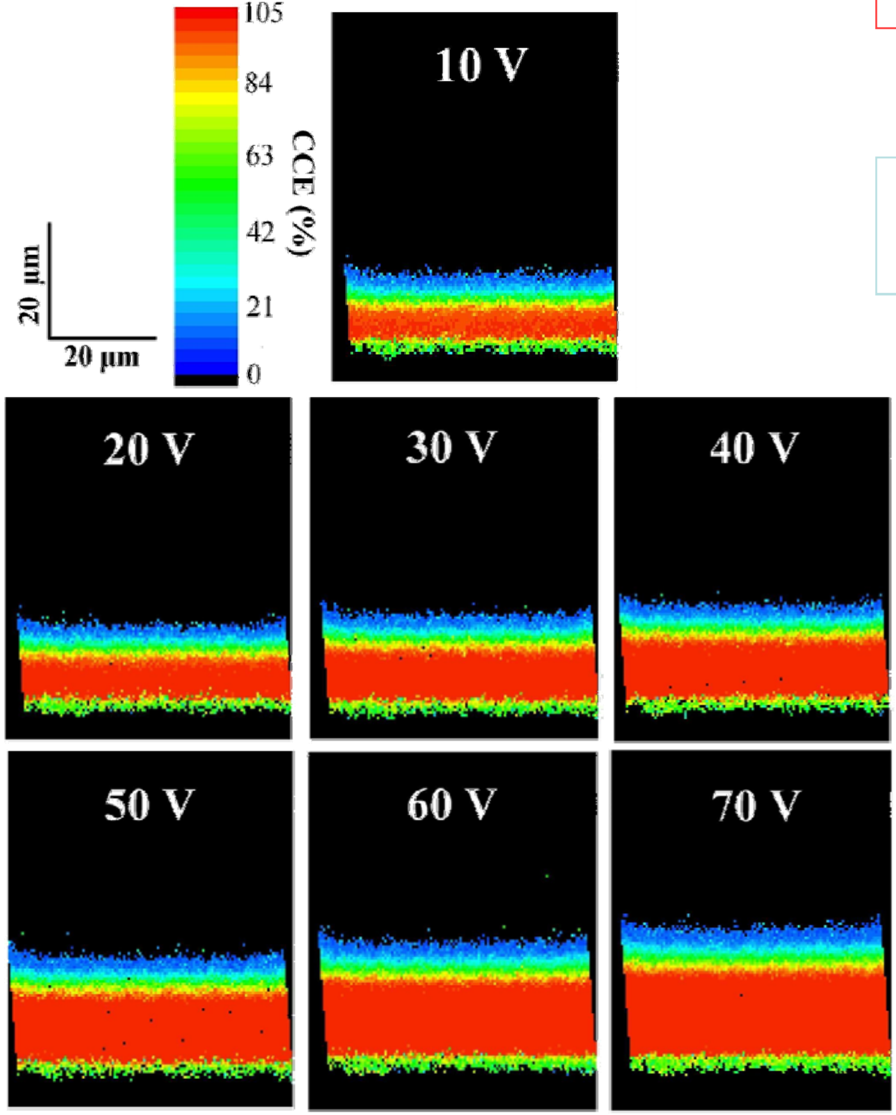
PRISTINE CONDITIONS



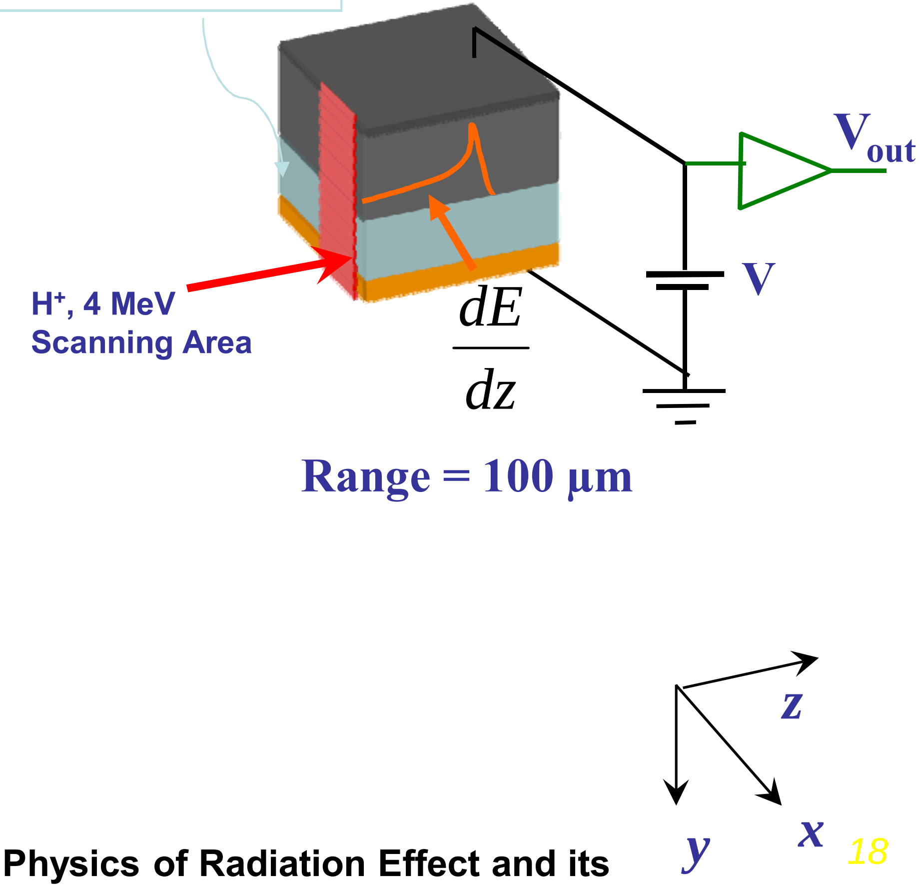
Charge collection efficiency
Vs.
Ion Fluence



Lateral IBIC



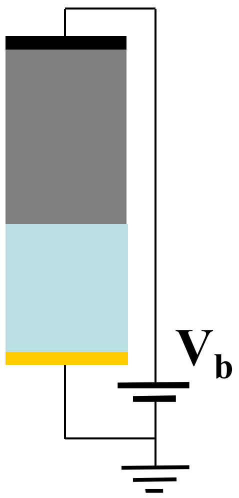
Protons, 4MeV on SiC

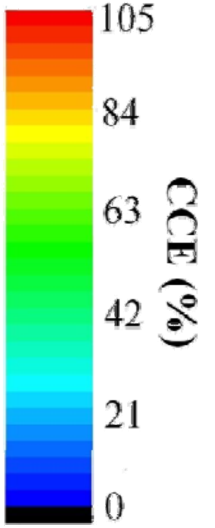


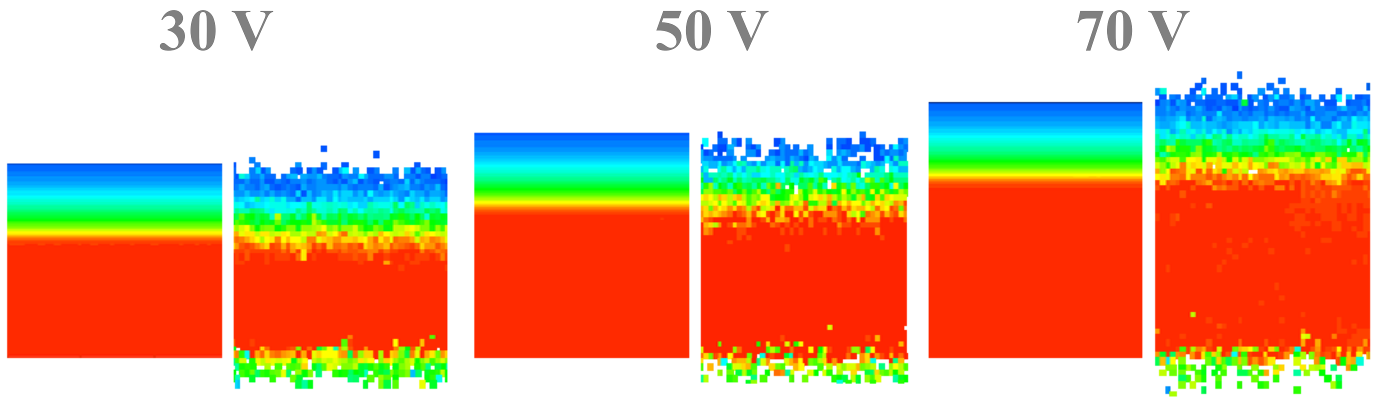
Numerical Simulations

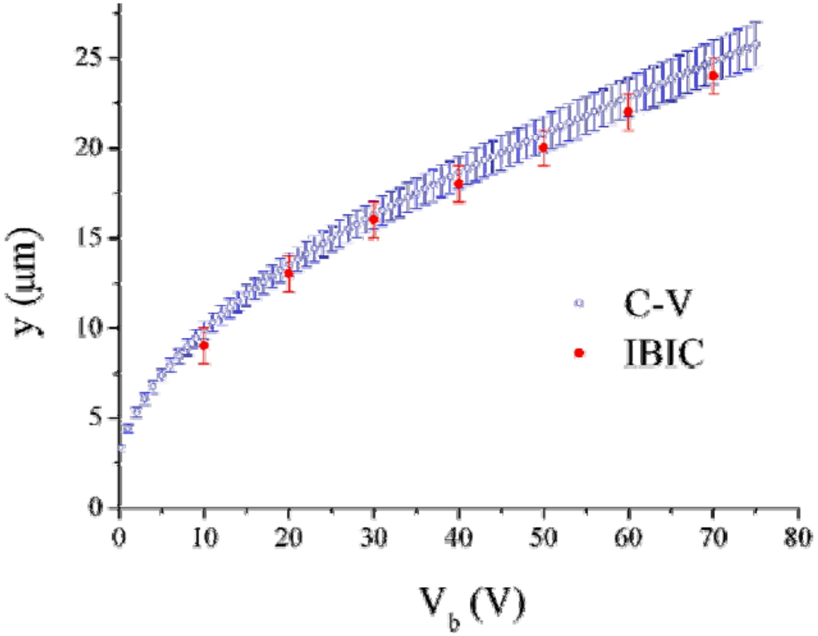
$L_p = (4{,}9 \pm 0{,}3)\,\mu m$

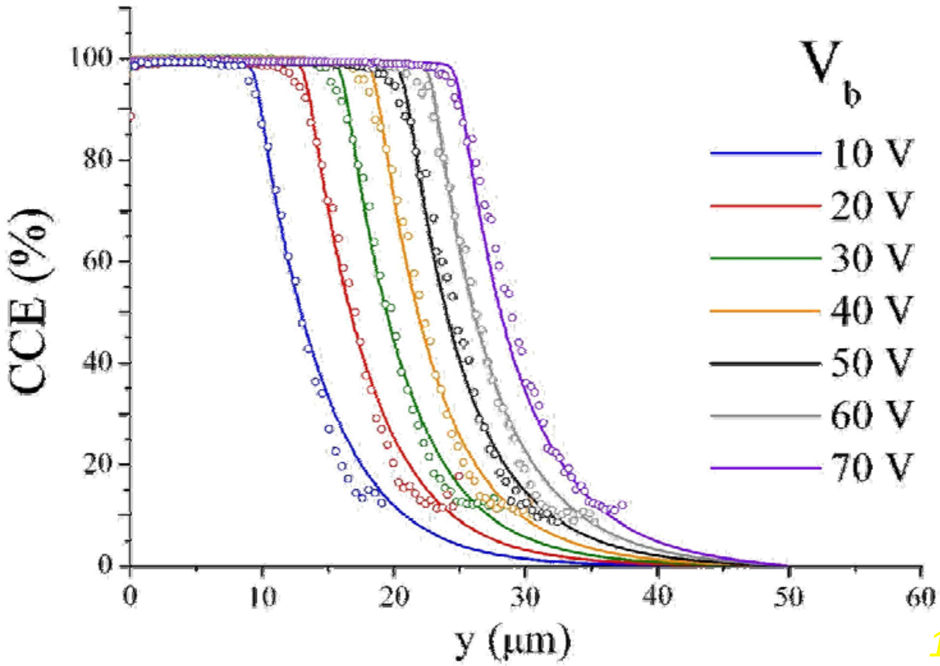
$\tau_p \approx 80\,ns$



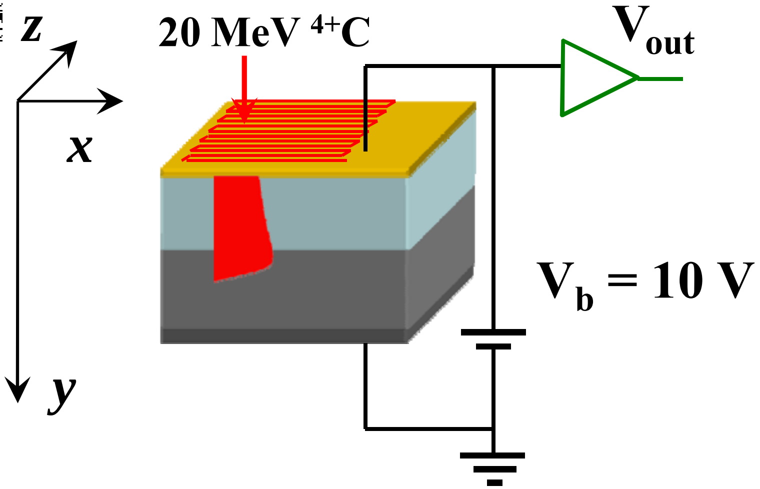


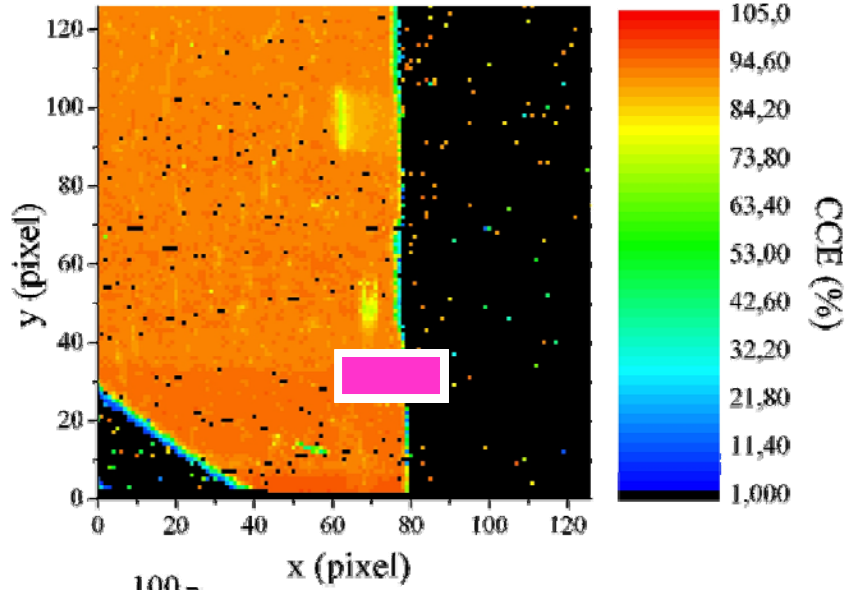


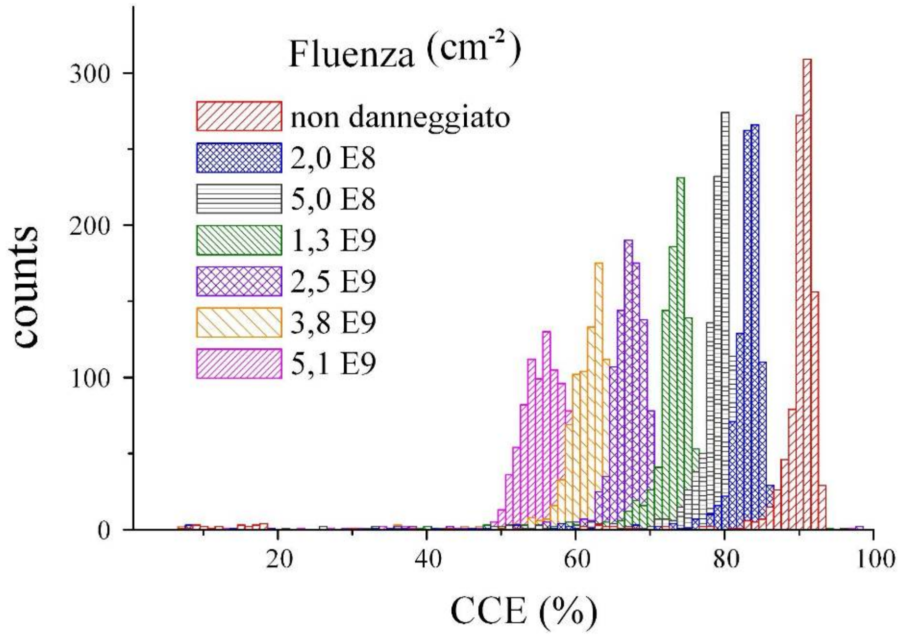


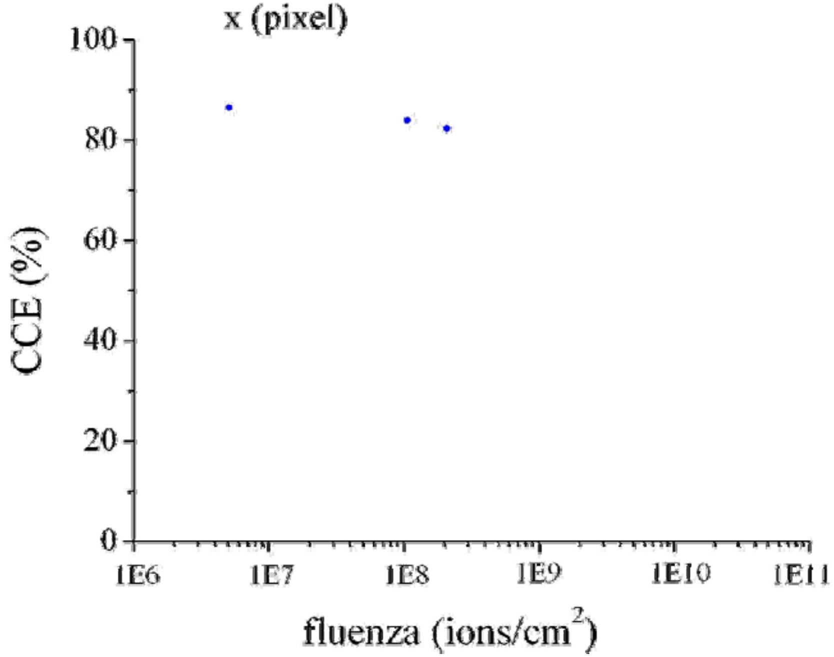


Radiation Damage; Frontal IBIC

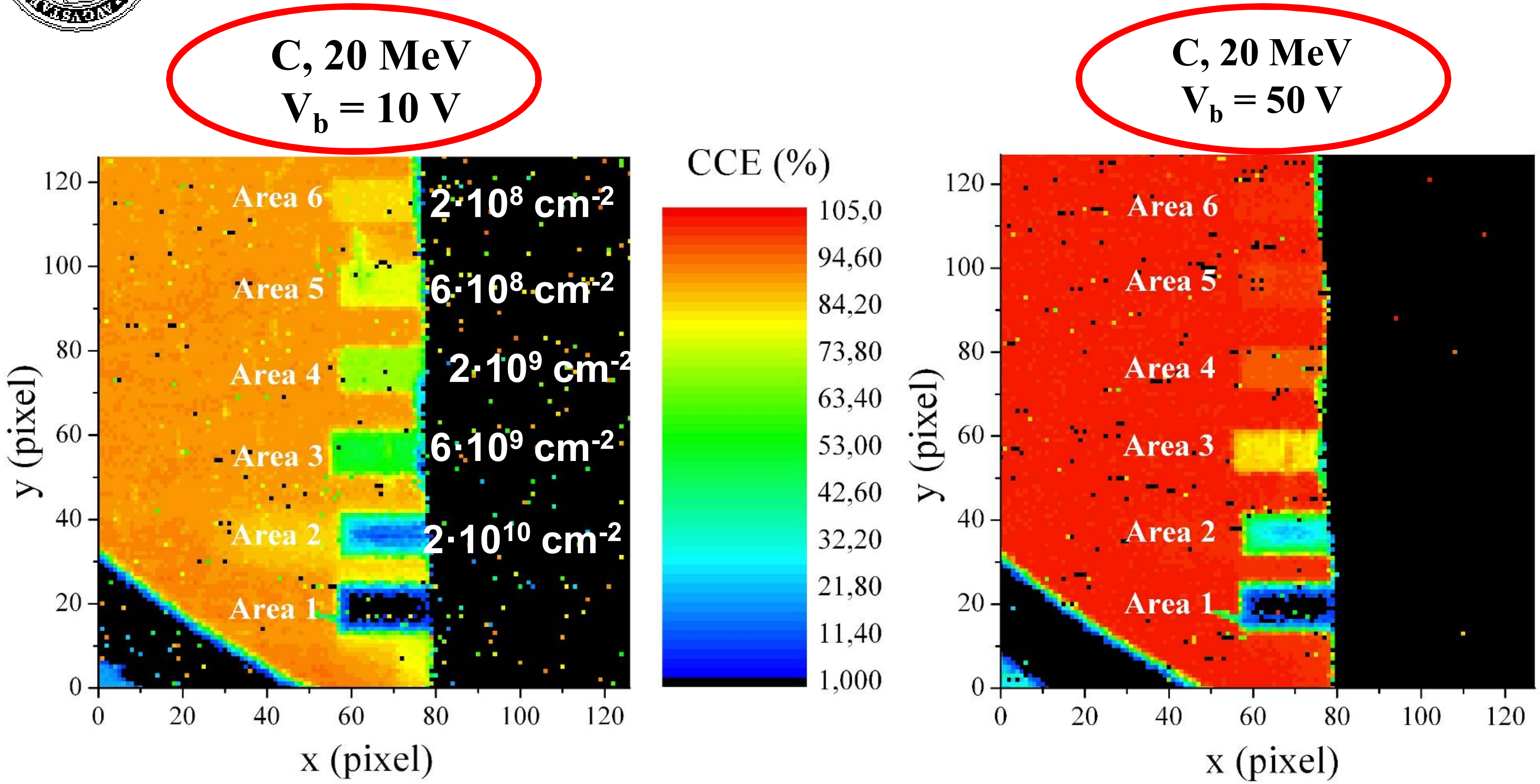








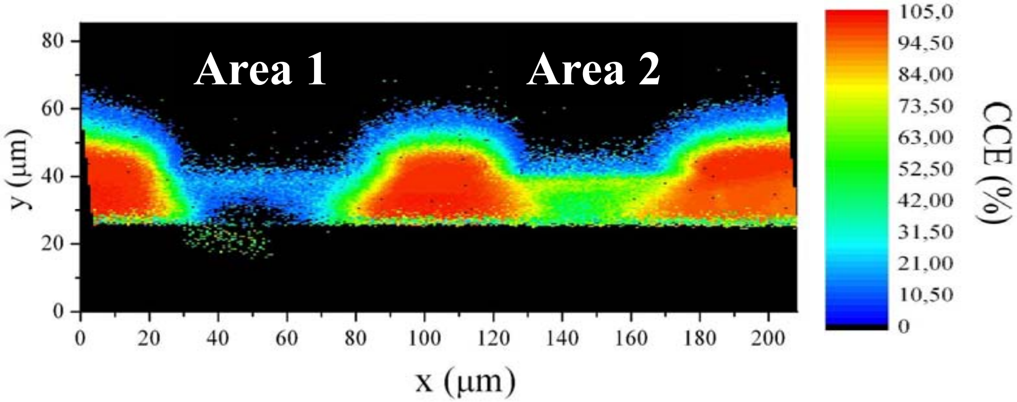
Frontal IBIC

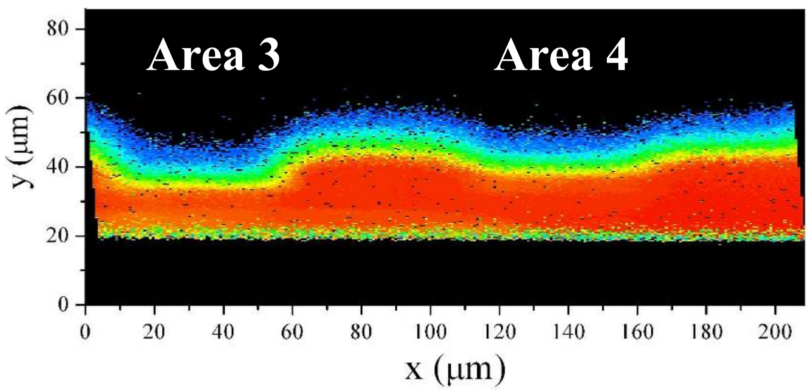


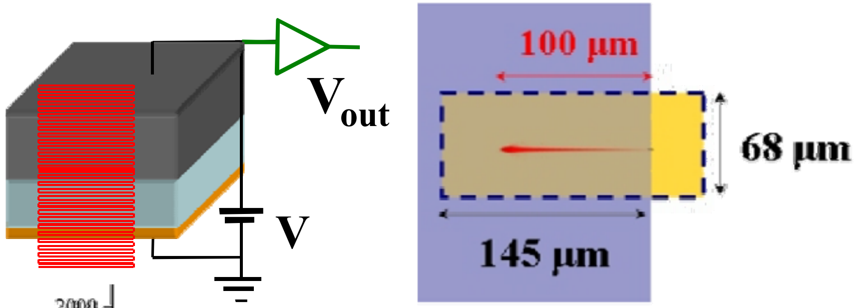
The CCE depends on the ion fluence and on the applied bias voltage

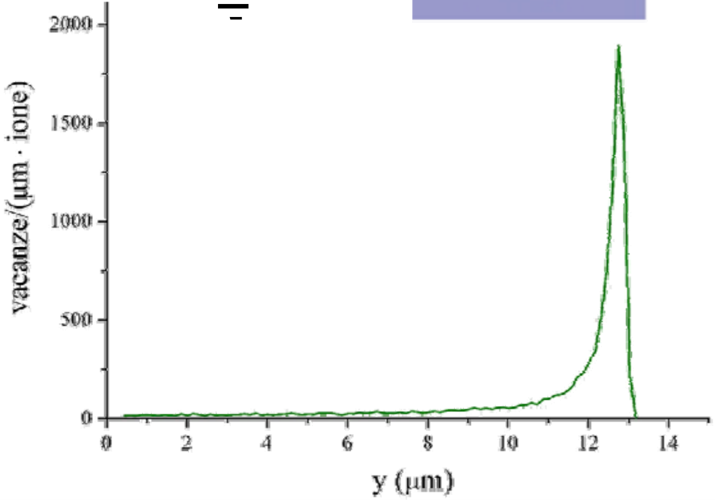
Lateral IBIC

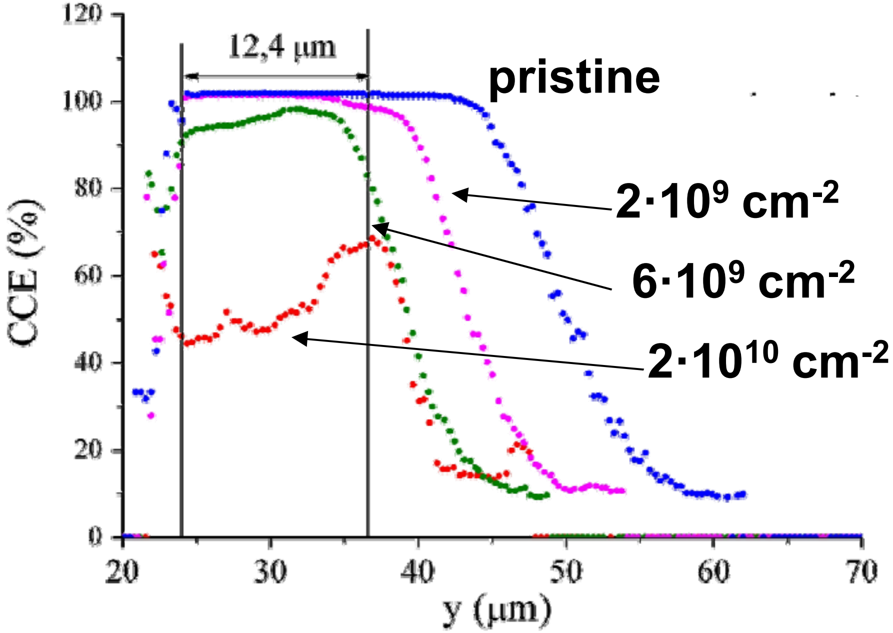
$V_b = 50$ V

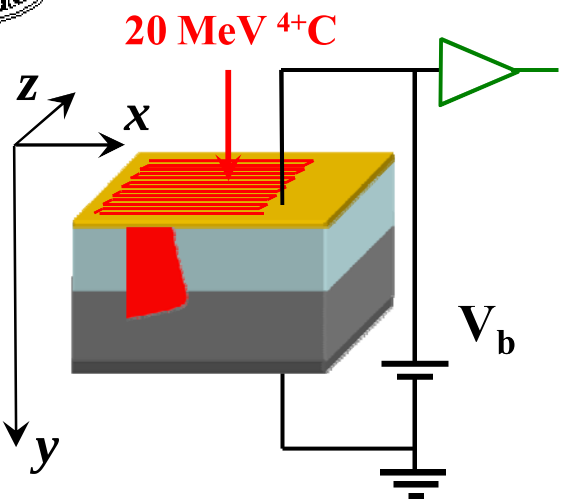




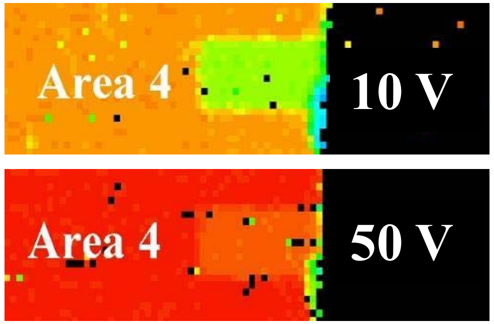


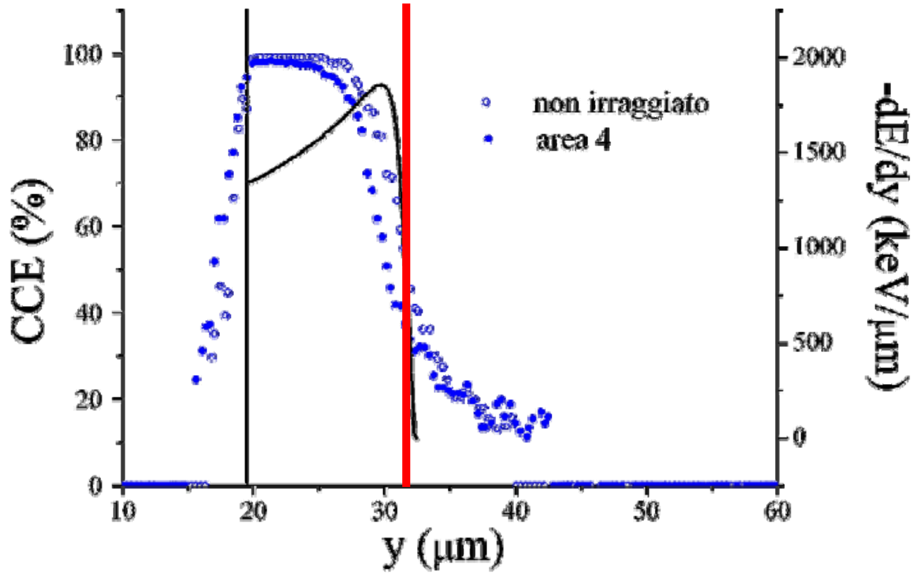


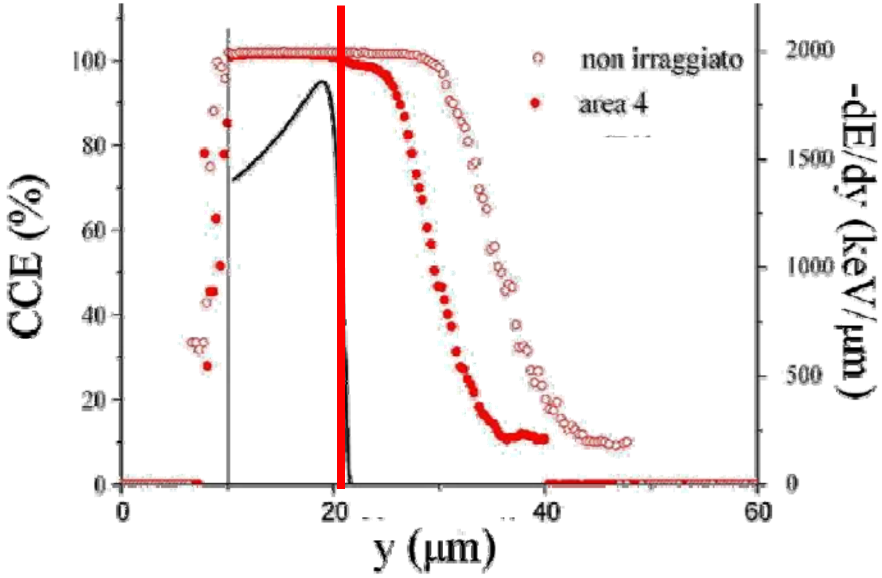




Frontal IBIC







10 V

50 V

Lateral IBIC

The performance degradation depends on

- Ion mass and energy
- Polarization state
- Free carrier generation profile (ion probe)

Shockley-Read-Hall Model

$$\frac{1}{\tau(\Phi)} = \frac{1}{\tau_0} + K \cdot \Phi$$

Definition of "radiation hardness"?

Displacement dose

$$\eta = \frac{Y}{Y_0} = 1 - K \cdot \Phi = 1 - K_{ed} \cdot D_d$$

IAEA Coordinate Research Programme (CRP) F11016 (2011-2015)
"Utilization of ion accelerators for studying and modeling of radiation induced defects in semiconductors and insulators"

COOPERATION AND MUTUAL UNDERSTANDING LEAD TO GROWTH AND GLOBAL ENRICHMENT

IAEA Coordinate Research Programme (CRP) F11016 (2011-2015)
"Utilization of ion accelerators for studying and modeling of radiation induced defects in semiconductors and insulators"

Overall Objective:

Use of ion accelerators for improved understanding of how radiation induced defects influence the electronic properties of semiconductor/insulator materials, leading to better understanding of how they degrade or improve the performances of devices in extreme and harsh radiation environments.

Specific Research Objective:

Deeper theoretical knowledge and experimental data on defects created by light and heavy ions; in terms of their type, density and effect on fundamental electronic properties of semiconductors and insulators.

Expected Research Outputs:

Definition of an experimental protocol to determine the key parameters for the characterization of the effects of radiation damage on semiconductor materials and devices.

Refined theoretical models for defect generation and for modelling their effect on electronic properties.

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Definition of an experimental protocol to determine the key parameters for the characterization of the effects of radiation damage on semiconductor materials and devices.

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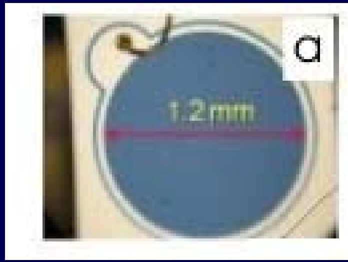
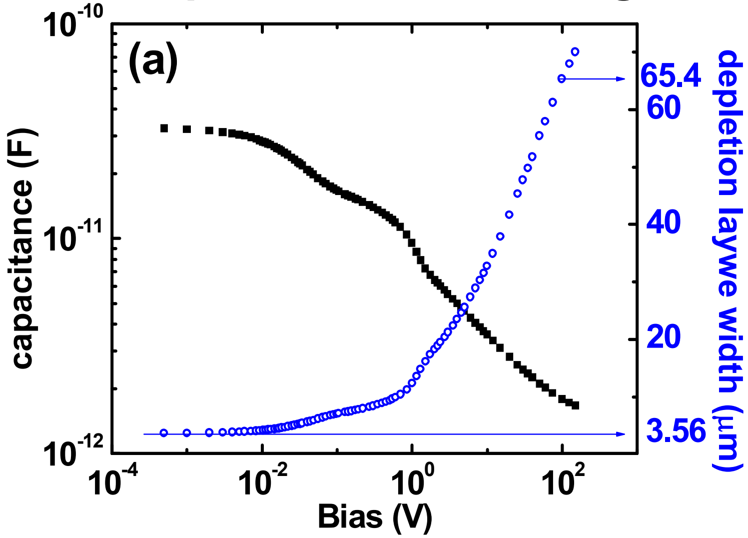
Definition of an experimental protocol

Hamamatsu
S5821 p-i-n diode



C-V characteristics
Depletion width-voltage

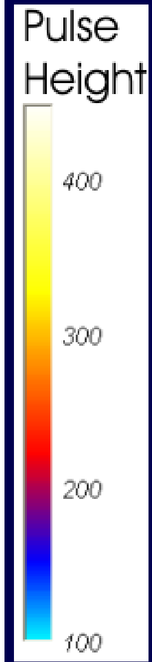


Experimental protocol

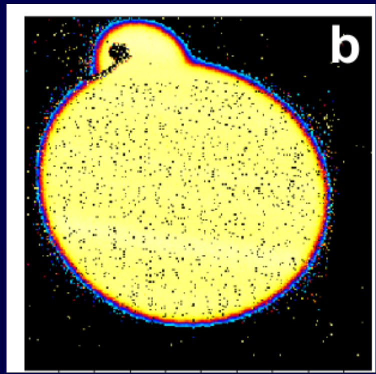
- ✓Commercial p-i-n diodes
- ✓Electrical characterization

Z. Pastuovic et al., IEEE Trans on Nucl. Sc. 56 (2009) 2457; APL (98) 092101 (2011)

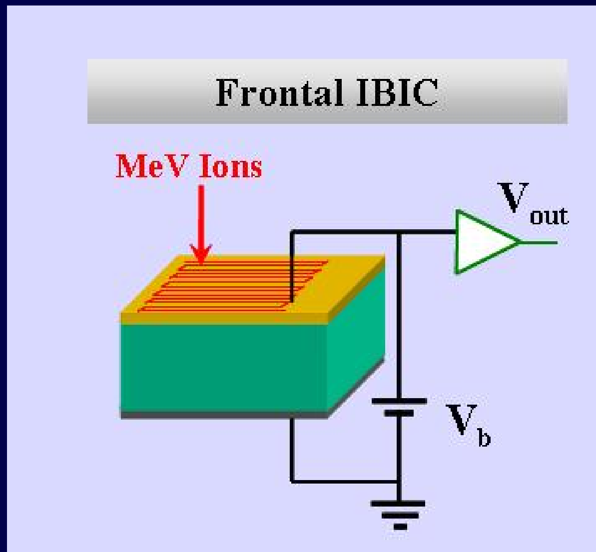
IBIC map on a pristine diode probed with a scanning 1.4 MeV He microbeam;



Hamamatsu S5821 p-i-n diode



Uniform CCE map



Experimental protocol

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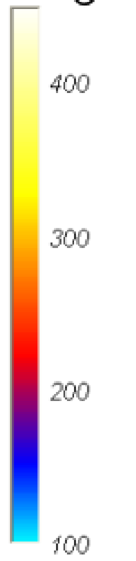
- ✓IBIC map on pristine sample

Z. Pastuovic et al., IEEE Trans on Nucl. Sc. 56 (2009) 2457; APL (98) 092101 (2011)

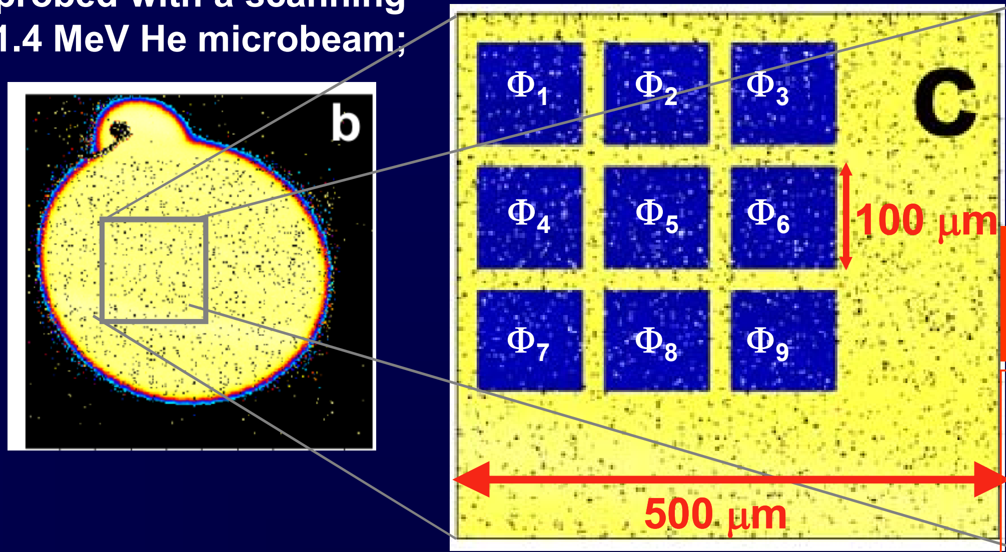
Pulse Height



Hamamatsu S5821 p-i-n diode

IBIC map on a pristine diode probed with a scanning 1.4 MeV He microbeam;

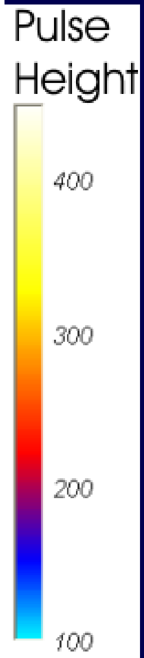
ZOOM in view of the selected area for focused ion beam irradiation at different fluences Φ



Experimental protocol

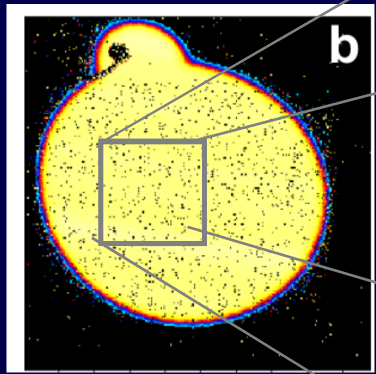
- ✓Commercial p-i-n diodes
- ✓Electrical characterization
- ✓IBIC map on pristine sample
- ✓Irradiation of 9 regions at different fluences

Z. Pastuovic et al., IEEE Trans on Nucl. Sc. 56 (2009) 2457; APL (98) 092101 (2011)

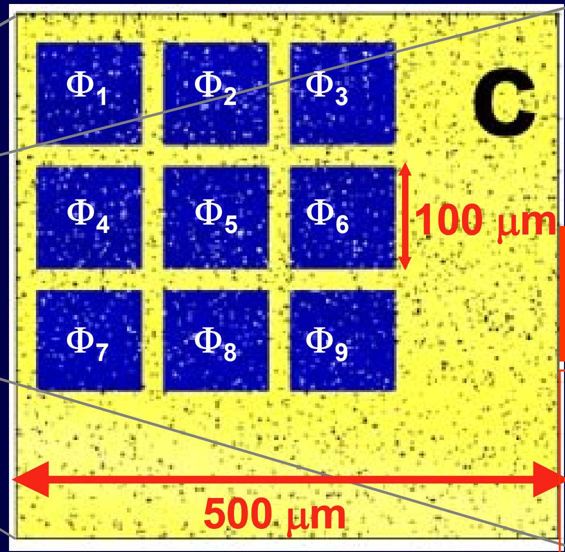


Hamamatsu S5821 p-i-n diode

IBIC map on a pristine diode probed with a scanning 1.4 MeV He microbeam;

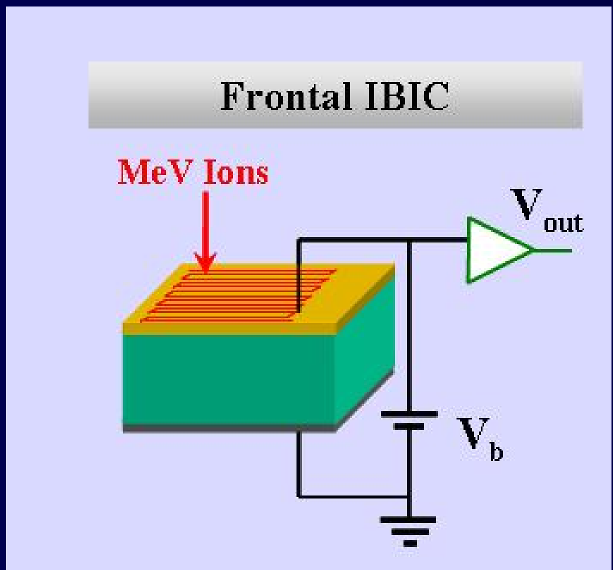


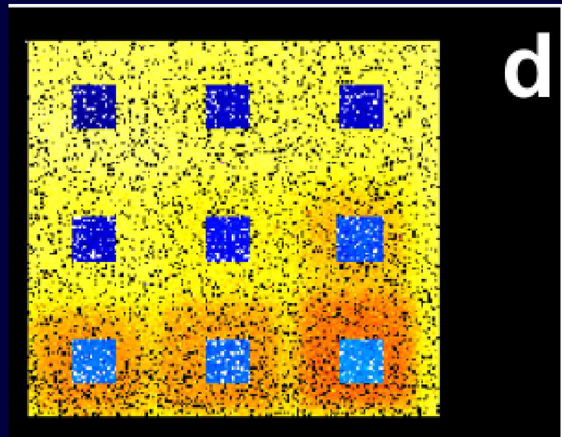
ZOOM in view of the selected area for focused ion beam irradiation at different fluences Φ



Experimental protocol

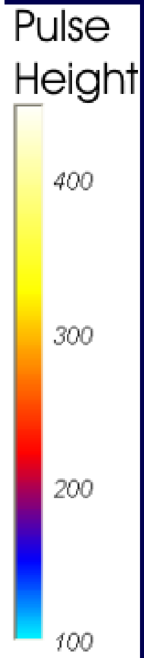
- ✓Commercial p-i-n diodes
- ✓Electrical characterization
- ✓IBIC map on pristine sample
- ✓Irradiatoin of 9 regions at different fluences
- ✓IBIC map of irradiated regions



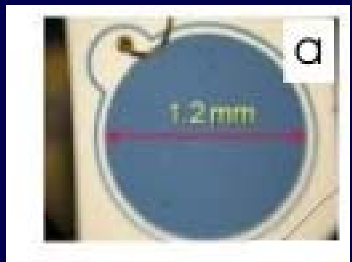


a measured 2D distribution of the IBIC signal amplitude after irradiation

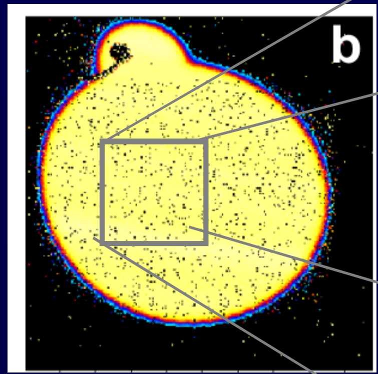
Z. Pastuovic et al., IEEE Trans on Nucl. Sc. 56 (2009) 2457; APL (98) 092101 (2011)



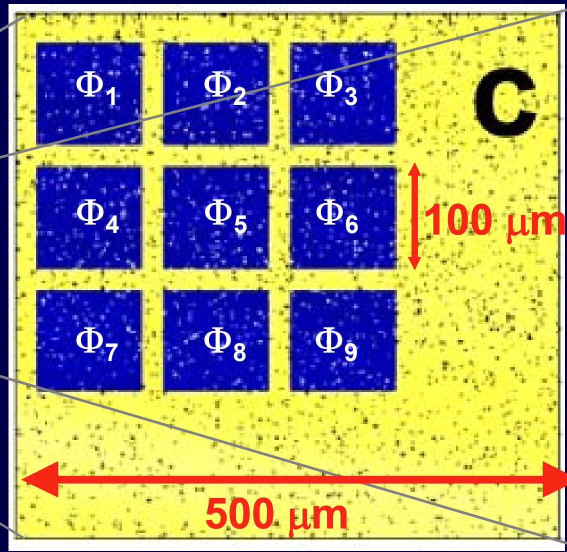
Hamamatsu S5821 p-i-n diode



IBIC map on a pristine diode probed with a scanning 1.4 MeV He microbeam;



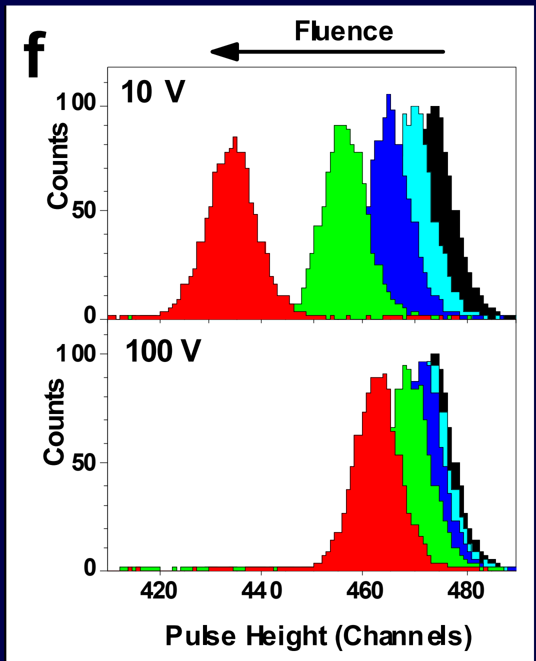
ZOOM in view of the selected area for focused ion beam irradiation at different fluences Φ

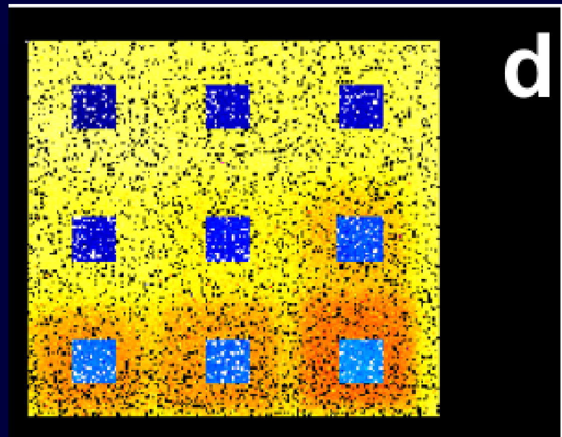


Experimental protocol

- ✓Commercial p-i-n diodes
- ✓Electrical characterization
- ✓IBIC map on pristine sample
- ✓Irradiatin of 9 regions at different fluences
- ✓IBIC map of irradiated regions
- ✓Average pulse height as function of the damage

IBIC spectra (bias voltage = 10 V and 100 V) from the central regions of four of the areas shown in Fig. c

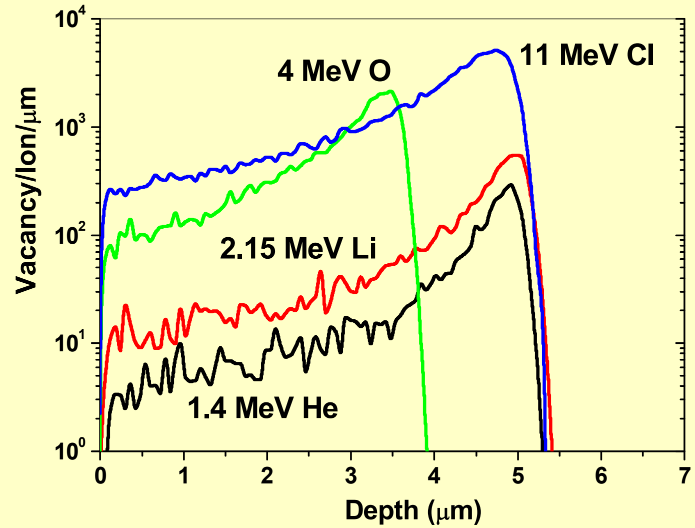




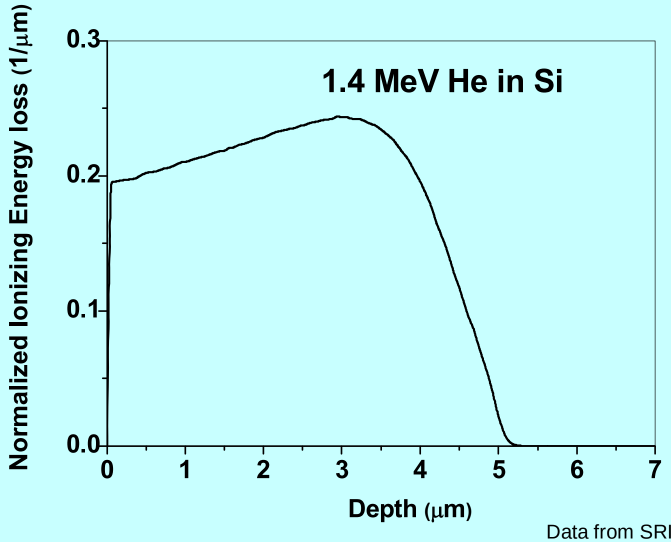
a measured 2D distribution of the IBIC signal amplitude after irradiation

Z. Pastuovic et al., IEEE Trans on Nucl. Sc. 56 (2009) 2457; APL (98) 092101 (2011)

Damaging Ions

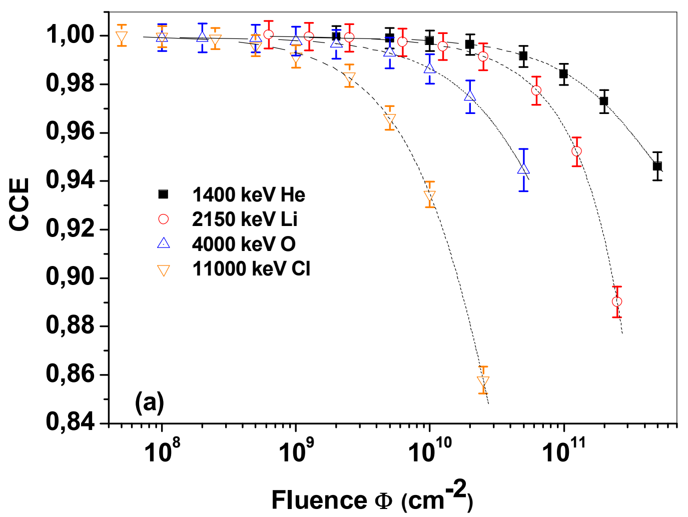


Ion Probe

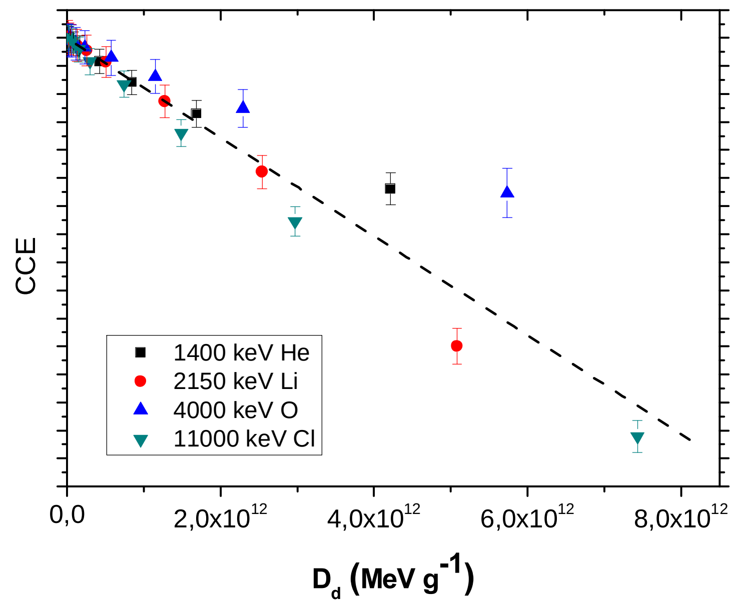


Data from SRIM

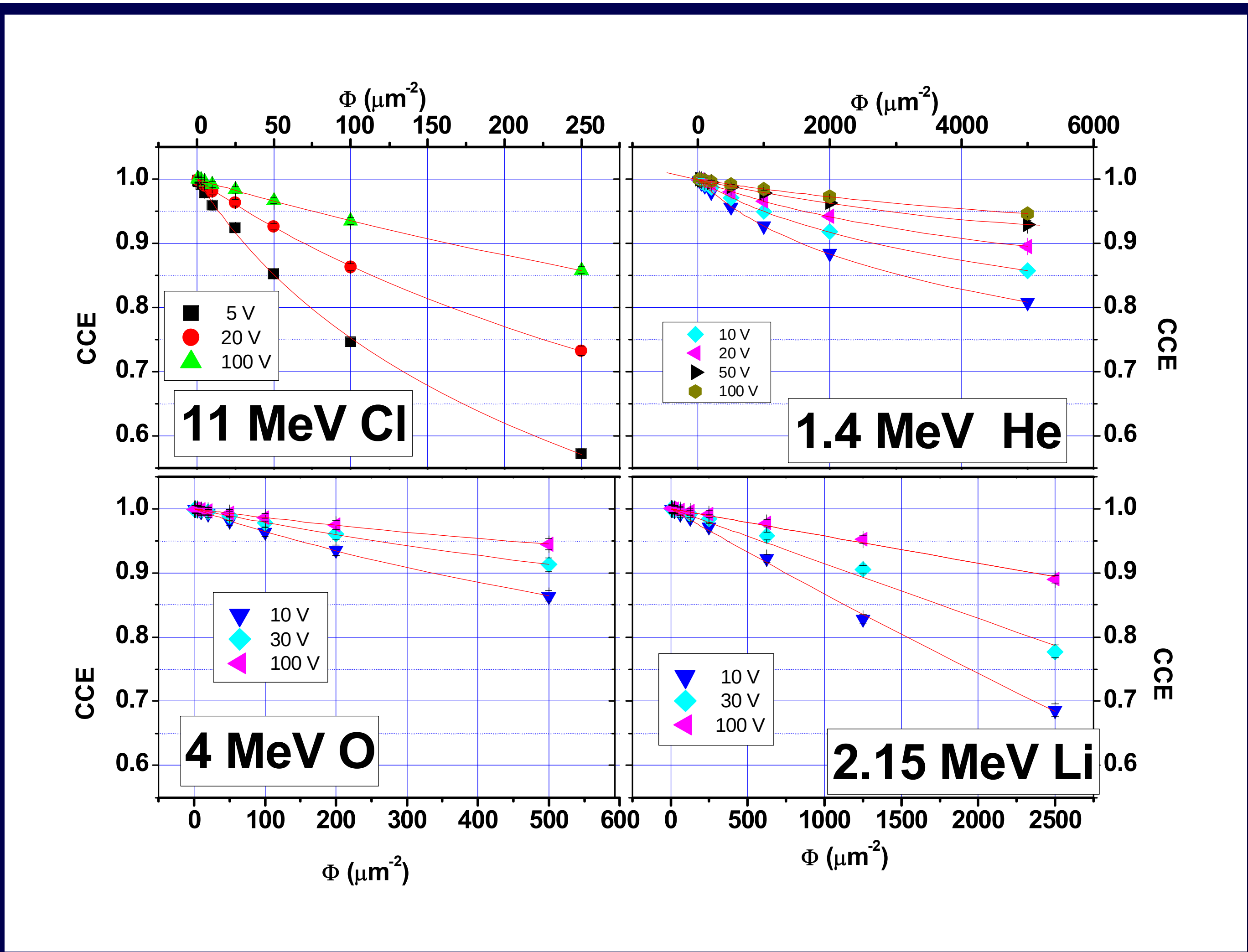
V_{bias}=100 V
Fully depleted device



CCE behavior in regions damaged with different ions vs. ion fluence (Φ); the dashed lines are parabolic fits as guides for eyes.



The same data points shown in Fig. 4 for plotted against the adjusted damage dose D_d.



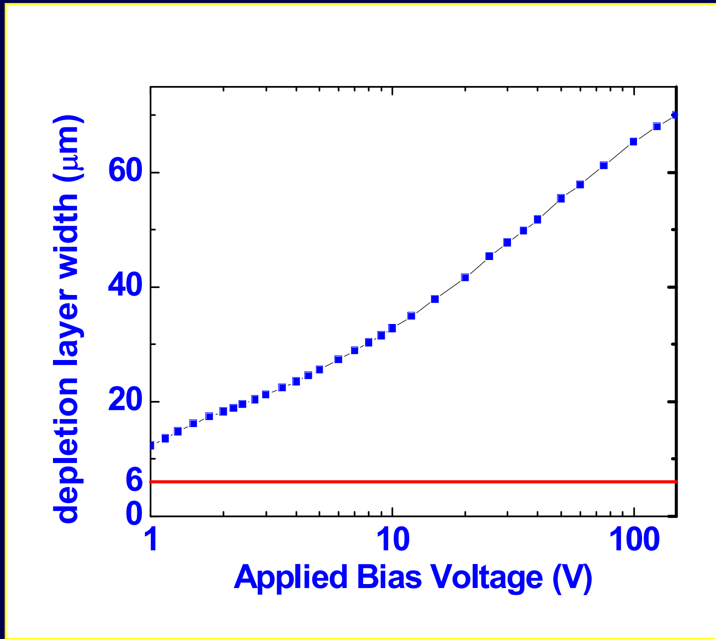
Measured CCE values for 1400 keV He ion detection in selected areas of biased Hamamatsu S5821 diodes irradiated with different fluences 1.4 MeV He, 2.15 MeV Li , 4.0 MeV O and 11 MeV Cl ions. The dashed lines are parabolic fits as guides for eyes.

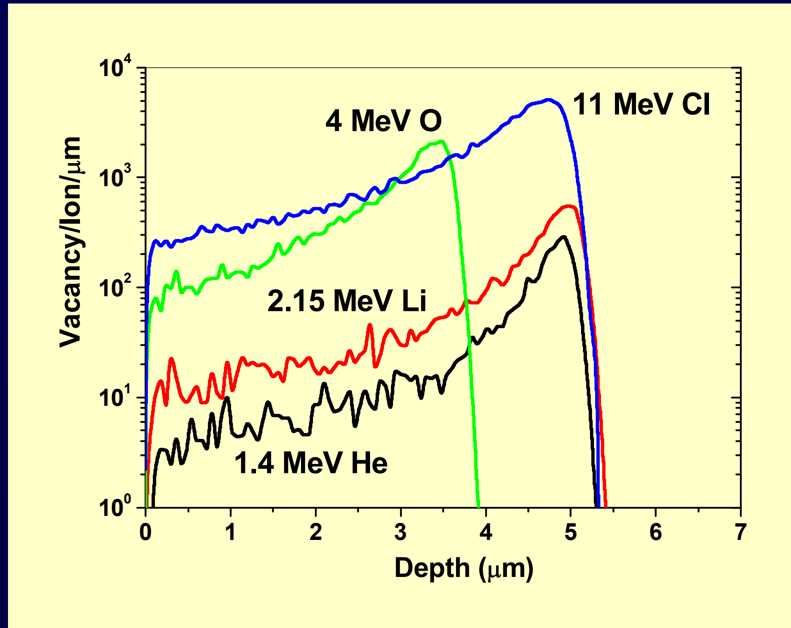
Expected Research Outputs:

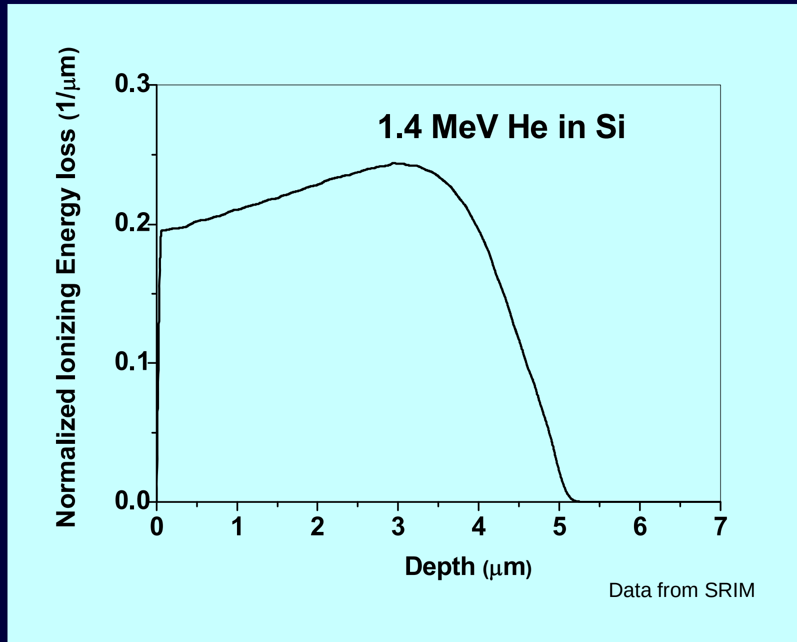
Definition of an experimental protocol to determine the key parameters for the characterization of the effects of radiation damage on semiconductor materials and devices.

Refined theoretical models for defect generation and for modelling their effect on electronic properties.

Fully depleted device





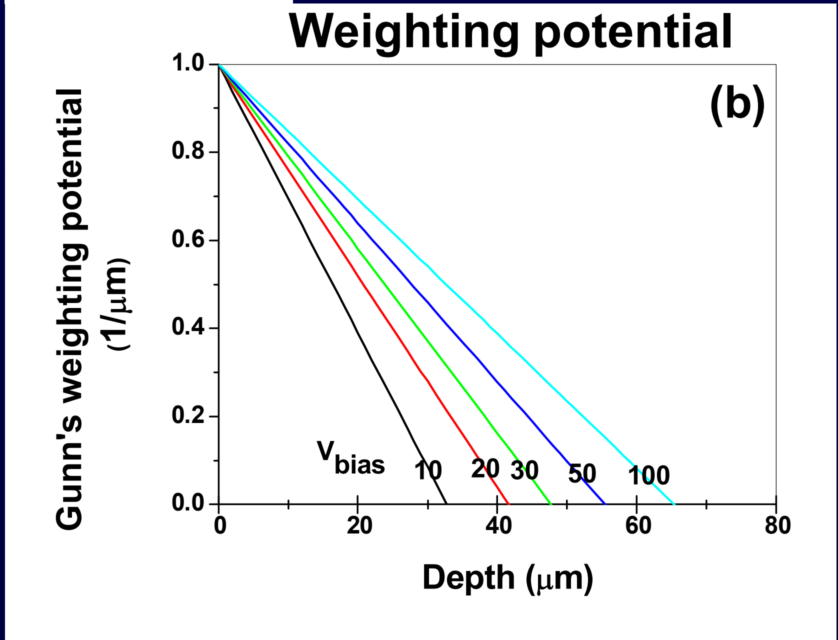


Fully depleted

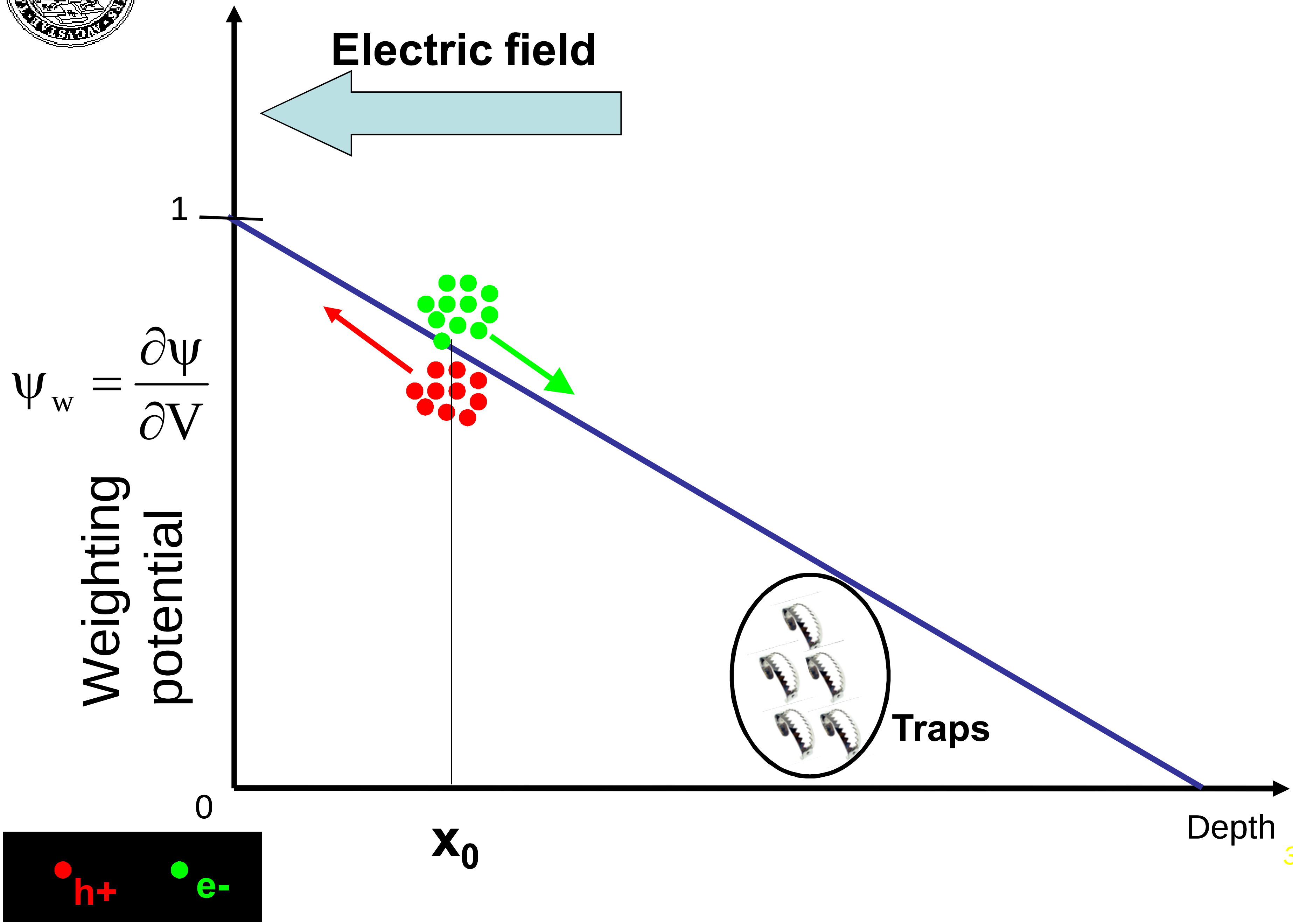
→ Ramo Theorem (no diffusion)

$$\varphi = \frac{\partial \psi}{\partial V} = \begin{cases} \left(1 - \frac{x}{w}\right) & \text{for } x < w \\ 0 & \text{for } x > w \end{cases}$$

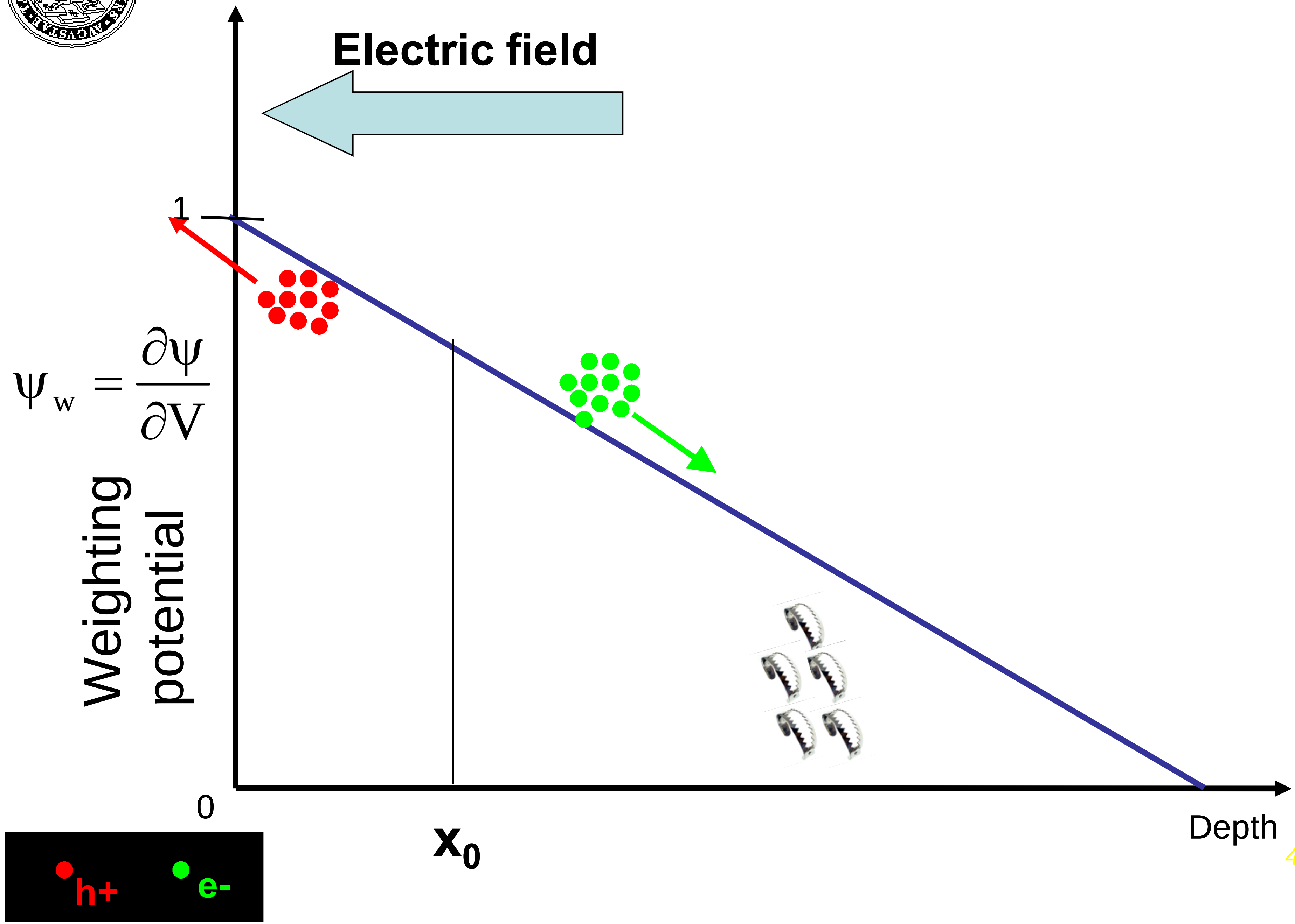
$$\left(\varphi = \frac{\partial \psi}{\partial V_{bias}}\right)$$



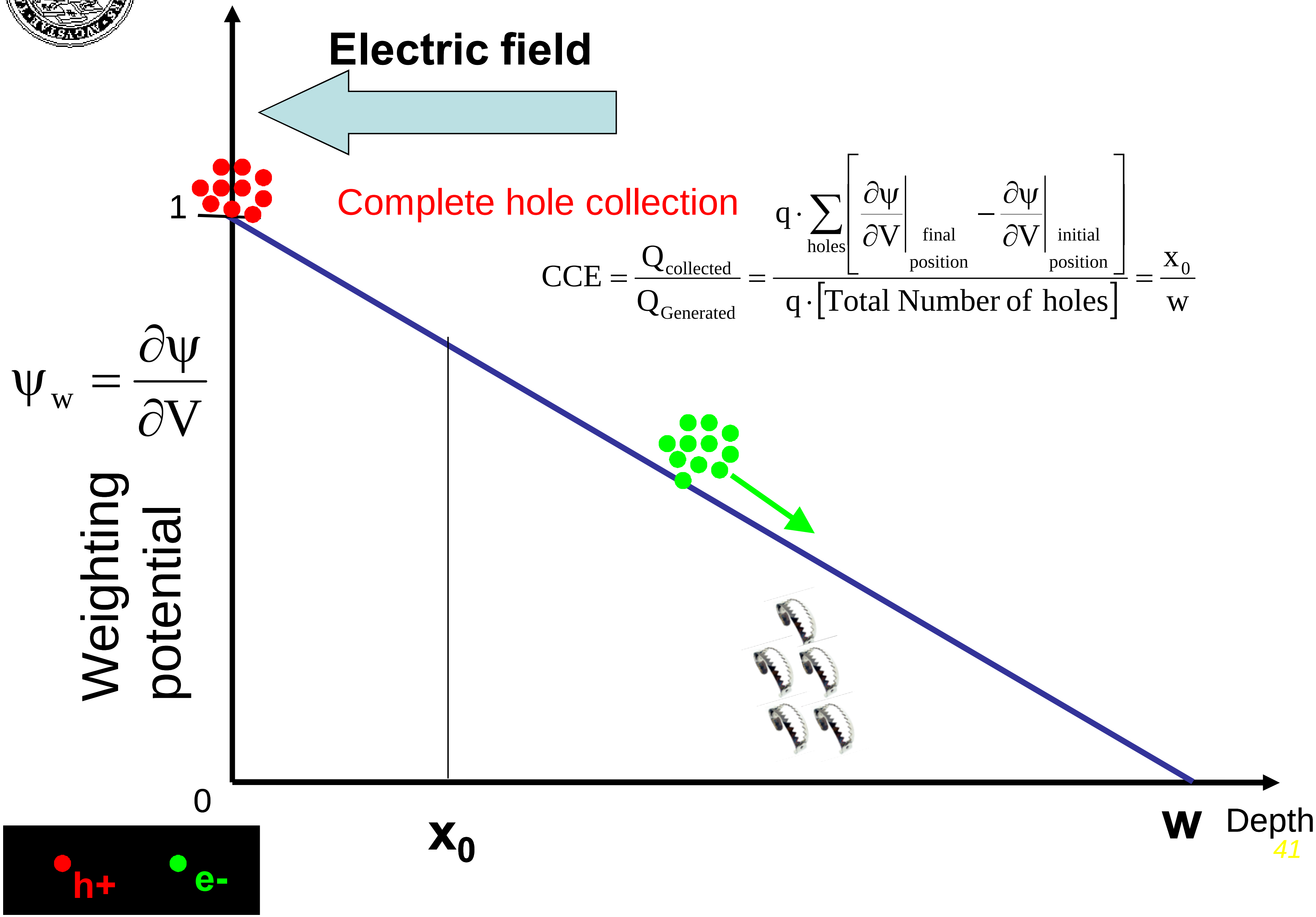
Effects of localized recombination centres



Effects of localized recombination centres



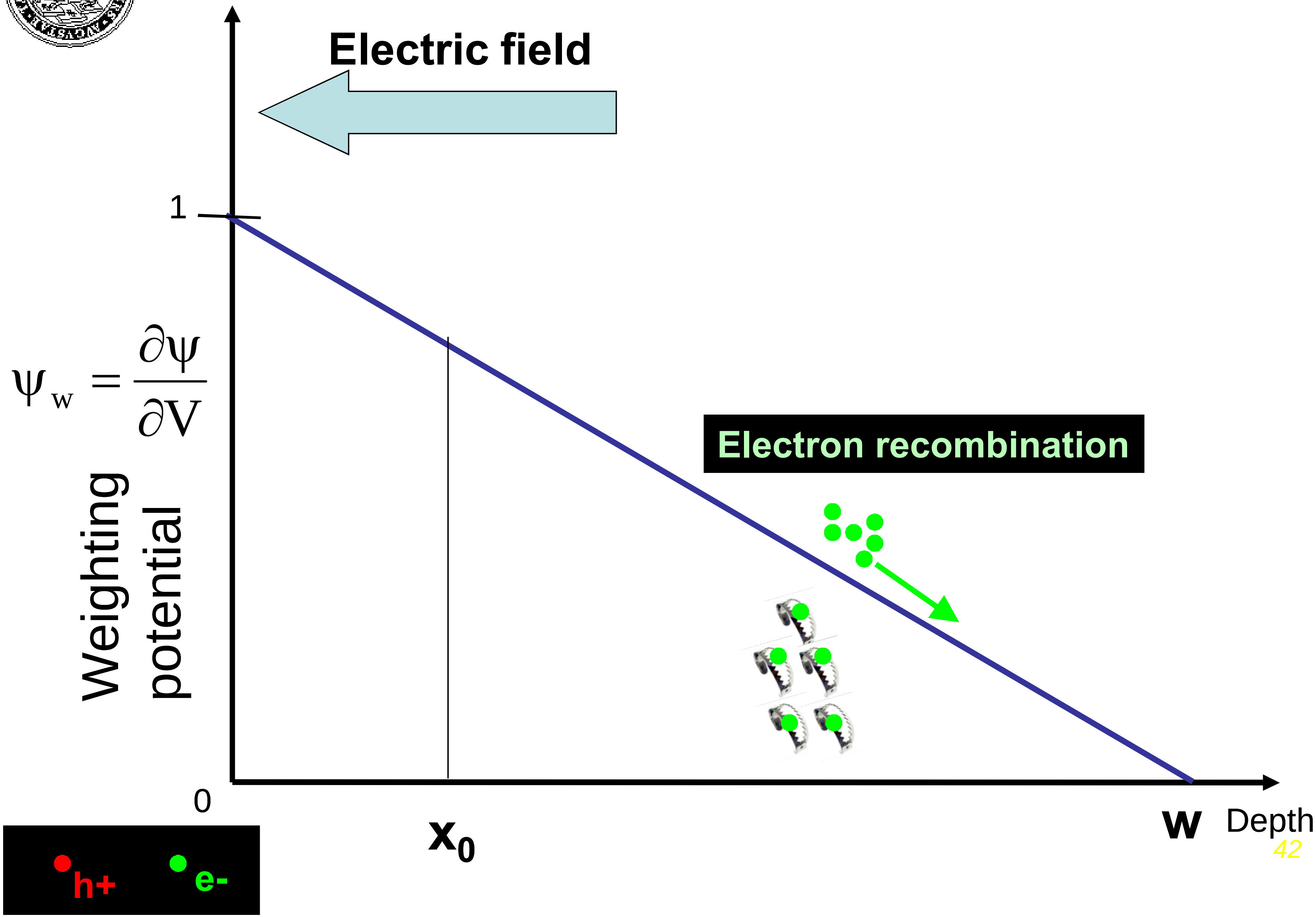
Effects of localized recombination centres



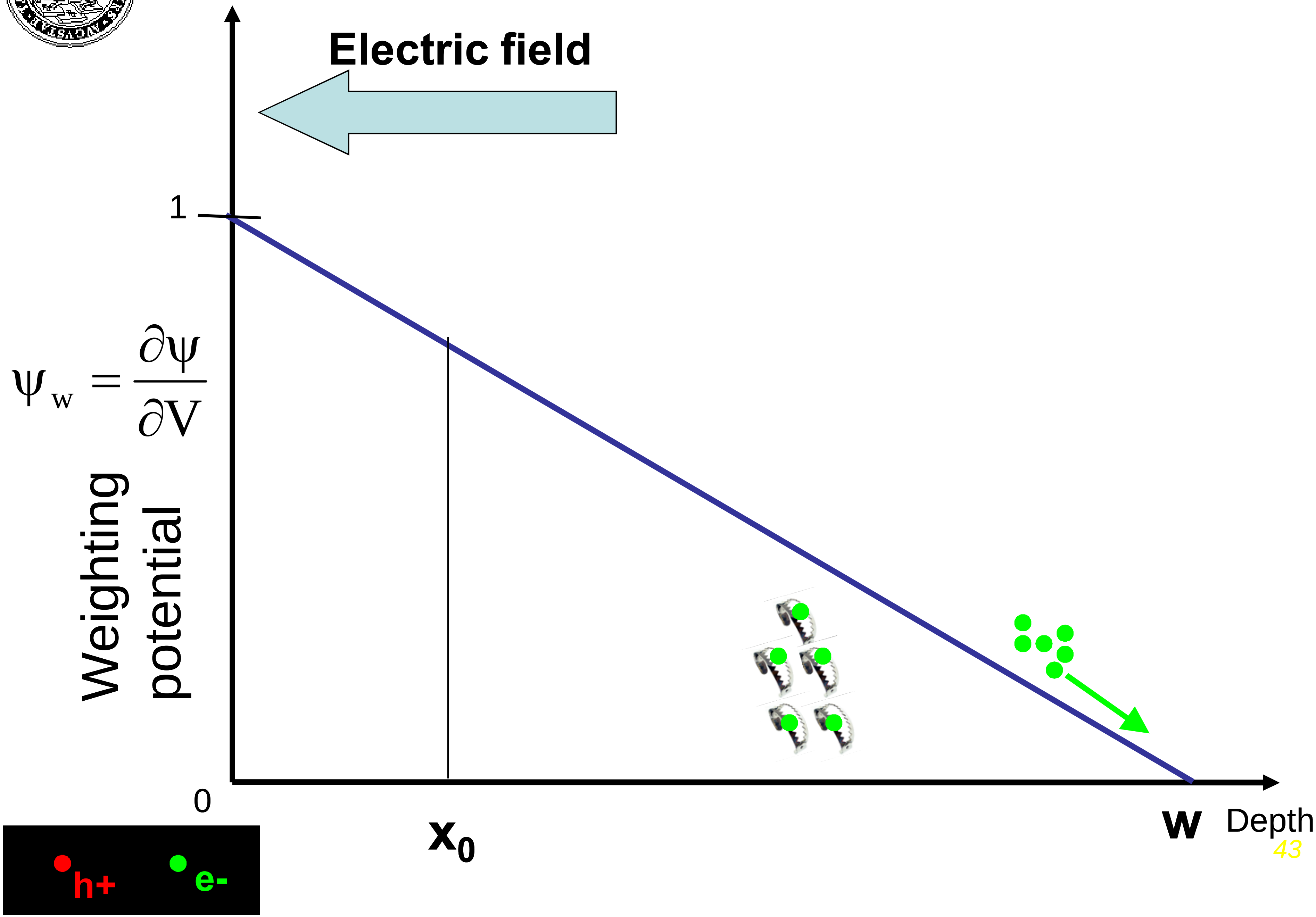
$$\psi_w = \frac{\partial \psi}{\partial V}$$

$$CCE = \frac{Q_{collected}}{Q_{Generated}} = \frac{q \cdot \sum_{holes} \left[\left.\frac{\partial \psi}{\partial V}\right|_{\substack{final \\ position}} - \left.\frac{\partial \psi}{\partial V}\right|_{\substack{initial \\ position}} \right]}{q \cdot [\text{Total Number of holes}]} = \frac{x_0}{w}$$

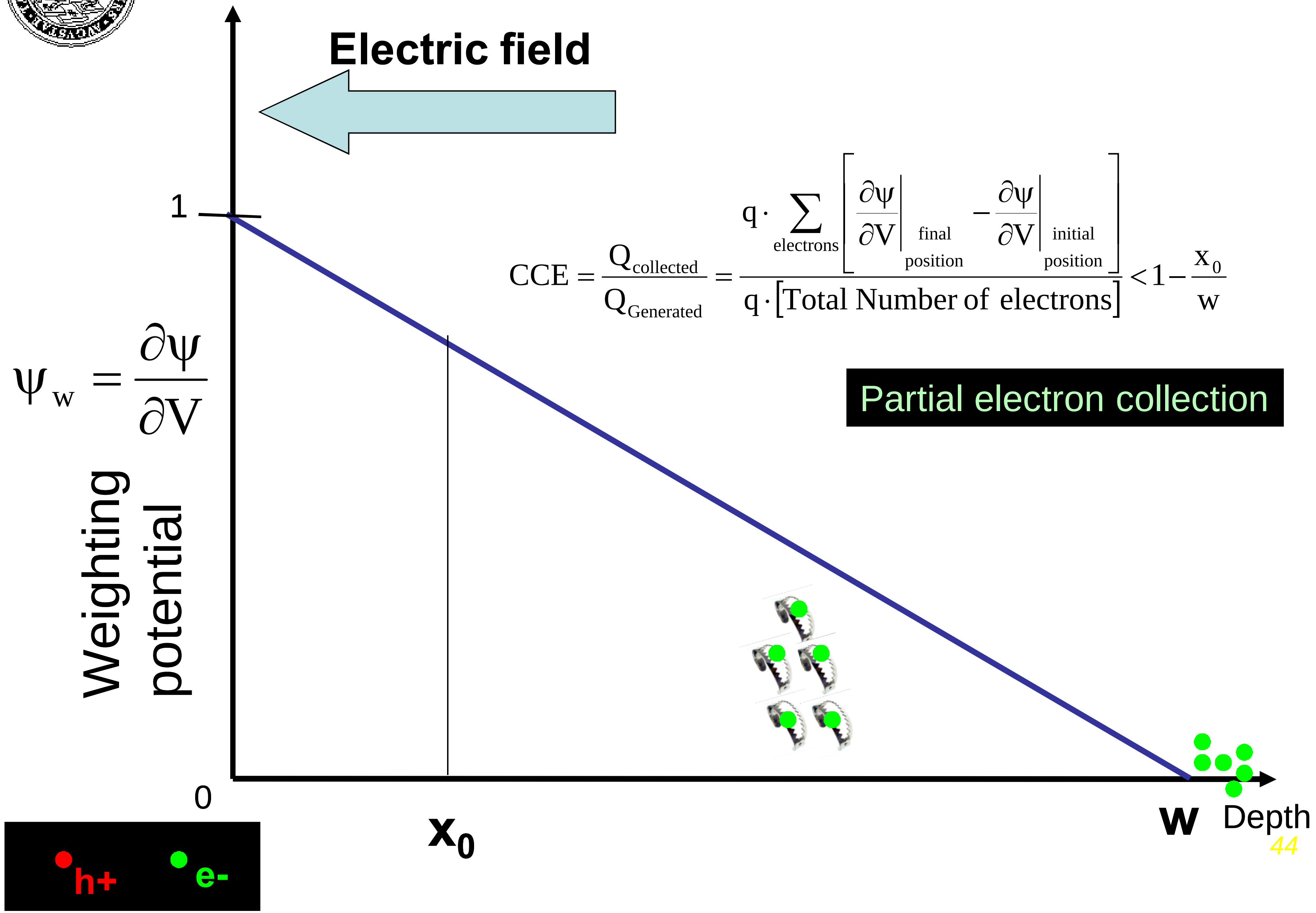
Effects of localized recombination centres



Effects of localized recombination centres



Effects of localized recombination centres



$$\psi_w = \frac{\partial \psi}{\partial V}$$

$$CCE = \frac{Q_{collected}}{Q_{Generated}} = \frac{q \cdot \sum_{electrons} \left[\left. \frac{\partial \psi}{\partial V} \right|_{\substack{final \\ position}} - \left. \frac{\partial \psi}{\partial V} \right|_{\substack{initial \\ position}} \right]}{q \cdot [\text{Total Number of electrons}]} < 1 - \frac{x_0}{w}$$

Shockley-Read-Hall model

Ion induced Trap density

capture cross section Of ion induced traps

$$\frac{1}{\tau} = N_{trap} \cdot \sigma \cdot v_{th} = N^{0}_{trap} \cdot \sigma^{0} \cdot v_{th} + N'_{trap} \cdot \sigma' \cdot v_{th} = \frac{1}{\tau_0} + N'_{trap} \cdot \sigma' \cdot v_{th}$$

Actual Carrier Lifetime

Thermal velocity ($\approx 10^7$ cm/s)

Trap density in pristine material

Carrier Lifetime in pristine material

effective capture cross section In pristine material

Shockley-Read-Hall model

$$\frac{1}{\tau} = \frac{1}{\tau_0} + N'_{trap} \cdot \sigma' \cdot v_{th}$$

Average number of active trap per vacancy

Ion induced Trap density

Vacancy profile (from SRIM)

$$N'(x) = k \cdot Vac(x)$$

Shockley-Read-Hall model

Average number of active trap per vacancy

Actual Carrier Lifetime

Carrier Lifetime in pristine material

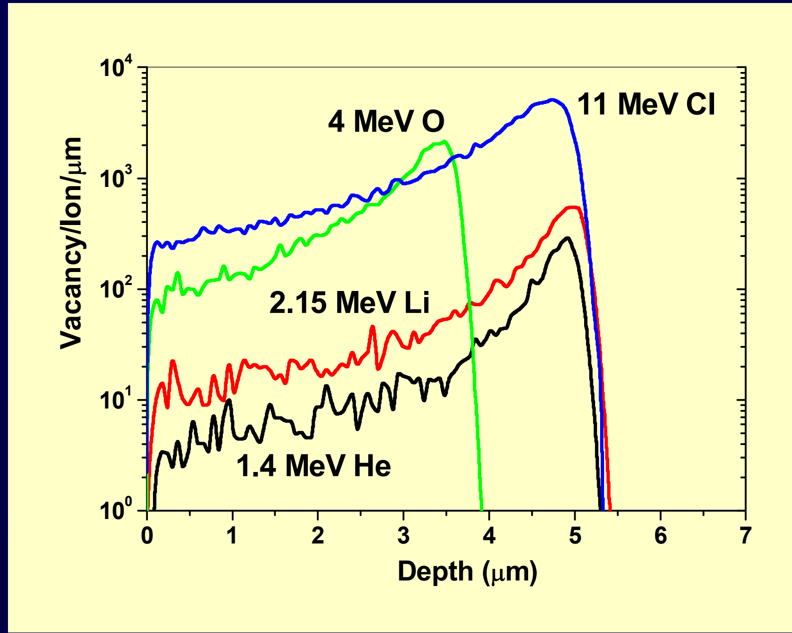
$$\tau(x,\Phi) = \frac{\tau_0(x)}{1 + k \cdot Vac(x) \cdot \sigma \cdot v_{th} \cdot \Phi \cdot \tau_0(x)}$$

Vacancy profile (from SRIM)

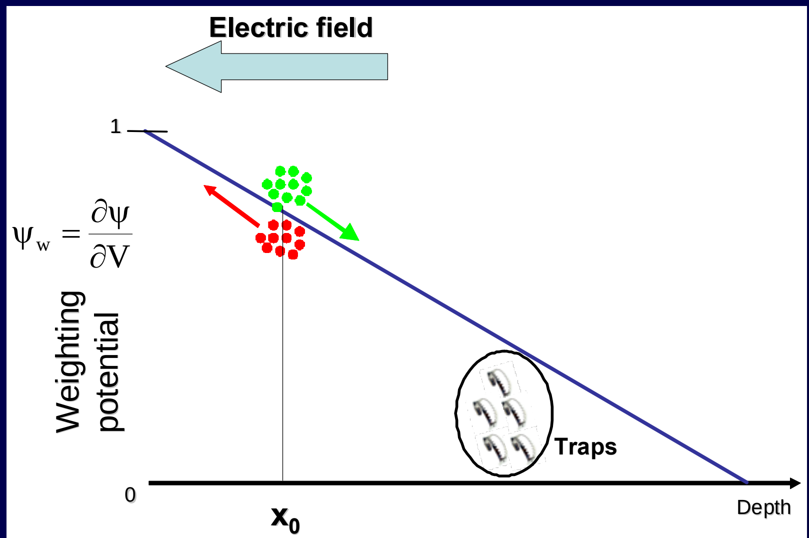
effective capture cross section (from DLTS)

Thermal velocity ($\approx 10^7$ cm/s)

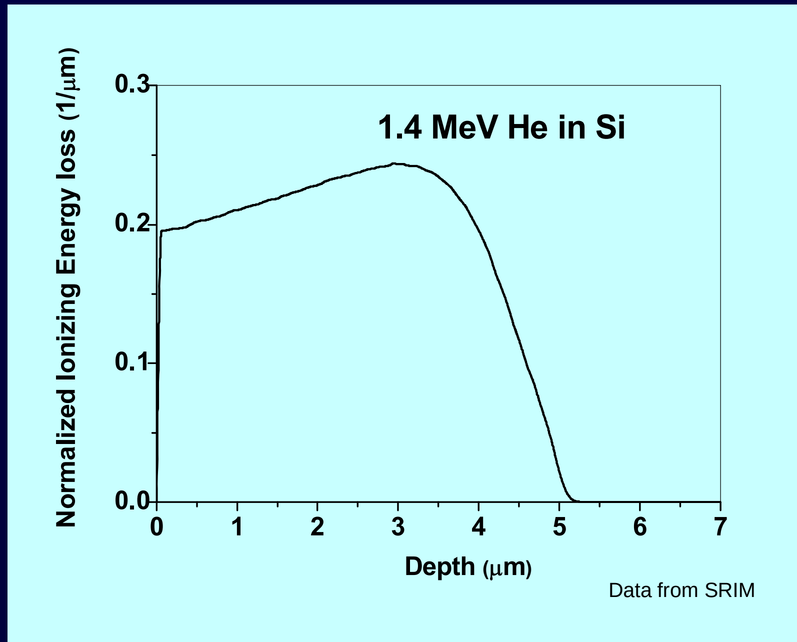
Ion fluence



Vacancy/Ion/μm
10^4
10^3
10^2
10^1
10^0
11 MeV Cl
4 MeV O
2.15 MeV Li
1.4 MeV He
0 1 2 3 4 5 6 7
Depth (μm)



Electric field
1
$\psi_w = \frac{\partial \psi}{\partial V}$
Weighting potential
Traps
0
x_0
Depth



Normalized Ionizing Energy loss (1/μm)
0.3
0.2
0.1
0.0
1.4 MeV He in Si
0 1 2 3 4 5 6 7
Depth (μm)
Data from SRIM

h+ e-

Ramo Theorem
(no diffusion)

Induced charge

from the motion of electrons

$$\eta(x,\Phi) = \frac{1}{w} \cdot \int_x^w dy \cdot \exp\left[-\int_x^y \frac{dz}{v_e(z) \cdot \tau_e(z,\Phi)} \right]$$

from the motion of holes

$$\eta(x,\Phi) = \frac{1}{w} \cdot \int_0^x dy \cdot \exp\left[-\int_y^x \frac{dz}{v_h(z) \cdot \tau_h(z,\Phi)} \right]$$

$$\text{Drift Length} = v_h(z) \cdot \tau_h(z,\Phi) >> w$$

Low damage level

Linearization

$$\eta(x,\Phi) \cong 1 - \Phi \cdot \left[\frac{k_e \cdot \sigma_e \cdot v_{th}}{w} \cdot \int_x^w dy \cdot \int_x^y \frac{Vac(z)}{v_e(z)} dz + \frac{k_h \cdot \sigma_h \cdot v_{th}}{w} \cdot \int_0^x dy \cdot \int_y^x \frac{Vac(z)}{v_h(z)} dz \right]$$

At high bias voltage
Hole contribution negligible
Saturation drift velocity
Semi-analytical expression

$$\mathrm{CCE}(\Phi) = 1 - k_e \cdot \sigma_e \cdot \frac{v_{th}}{\langle v_e \rangle} \cdot \left\{ \int_0^w dz \cdot \left[\tilde{E}_{Ion}(z) \cdot \mathrm{Vac}(z) \cdot \left(1 - \frac{z}{w}\right) \right] \right\} \cdot \Phi \equiv 1 - K_e^* \cdot \Phi_e^*$$

Ion probe energy loss

Vacancy profile

Weighting potential

$$\Phi^* = \text{Effective Fluence} = \int_0^w dz \cdot \left[\tilde{E}_{Ion}(z) \cdot \mathrm{Vac}(z) \cdot \left(1 - \frac{z}{w}\right) \right]$$

$$K_e^* = \text{effective damage factor} = k_e \cdot \sigma_e \cdot \frac{v_{th}}{\langle v_e \rangle}$$

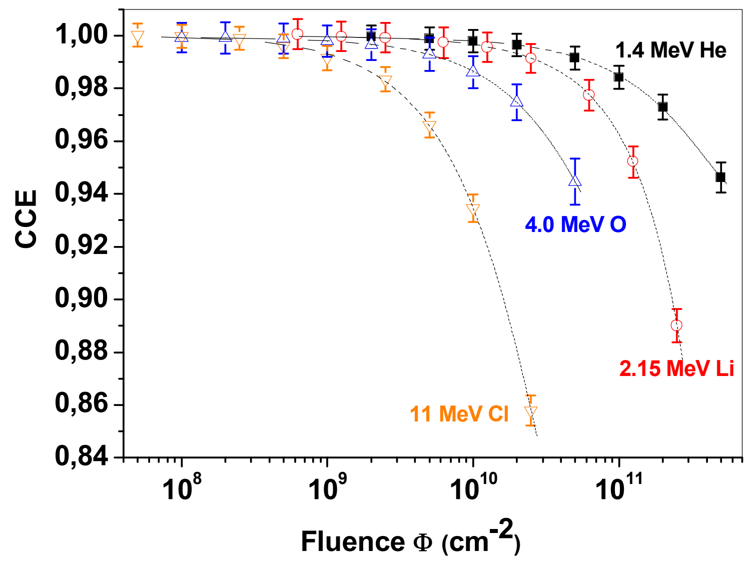
Average drift velocity

Average number of active trap per vacancy

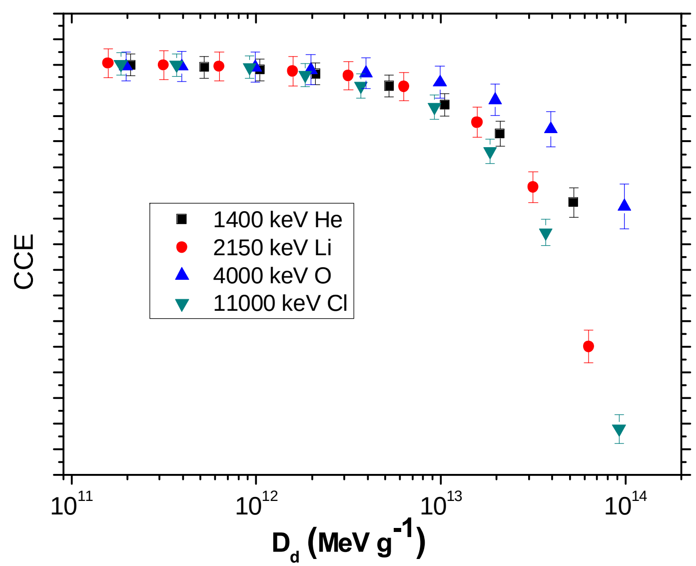
capture cross section of ion induced traps

V_{bias}=100 V

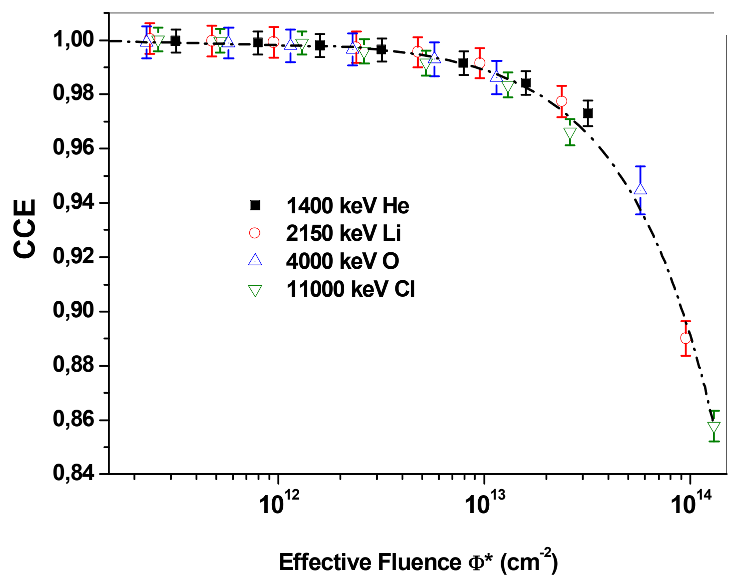
CCE vs Φ

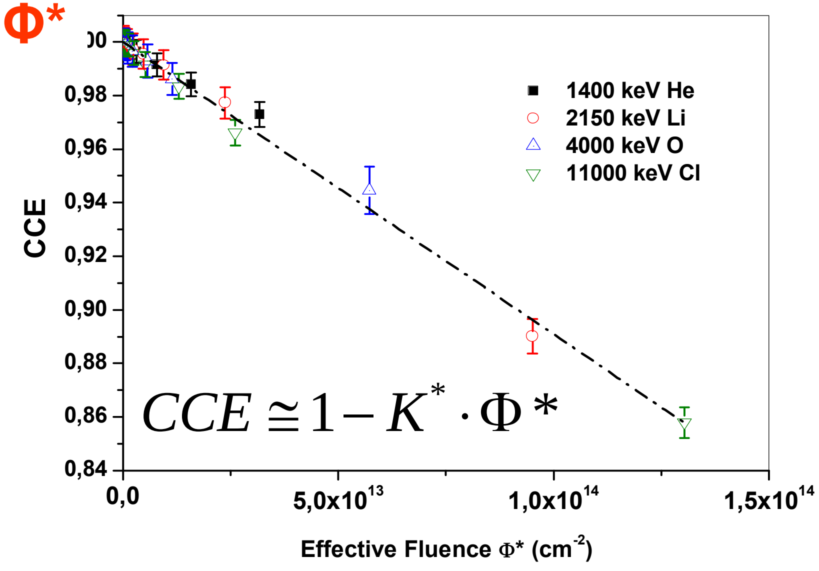


CCE vs D_d

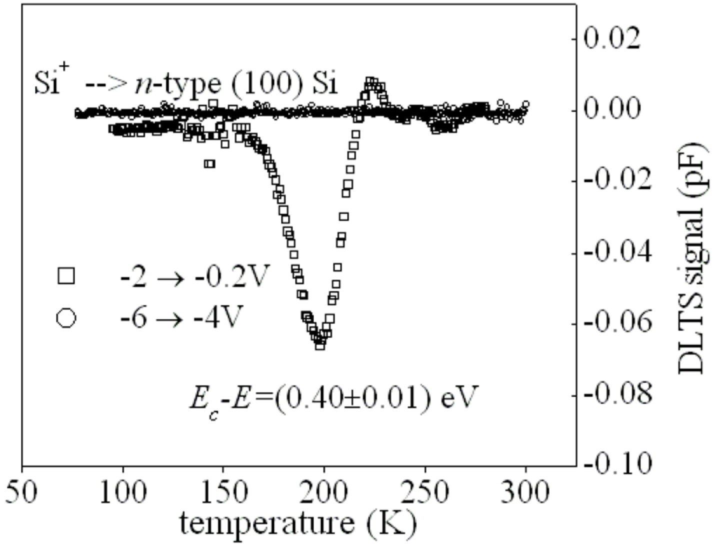


CCE vs Φ*





$$CCE \cong 1 - K^{*} \cdot \Phi^{*}$$



DLTS measurements

singly V2(−/0) negatively charged divacanc

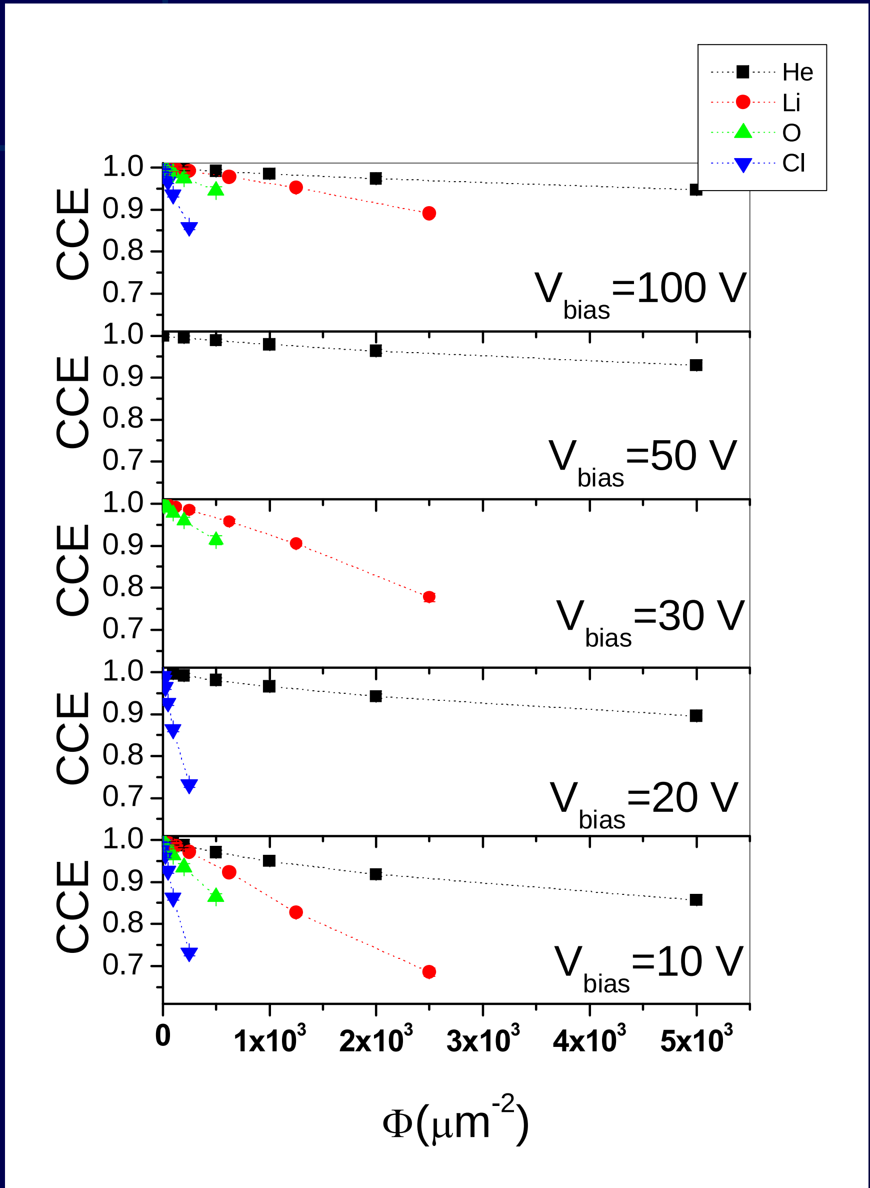
$\sigma_e \approx 5 \cdot 10^{-15}$ cm^2

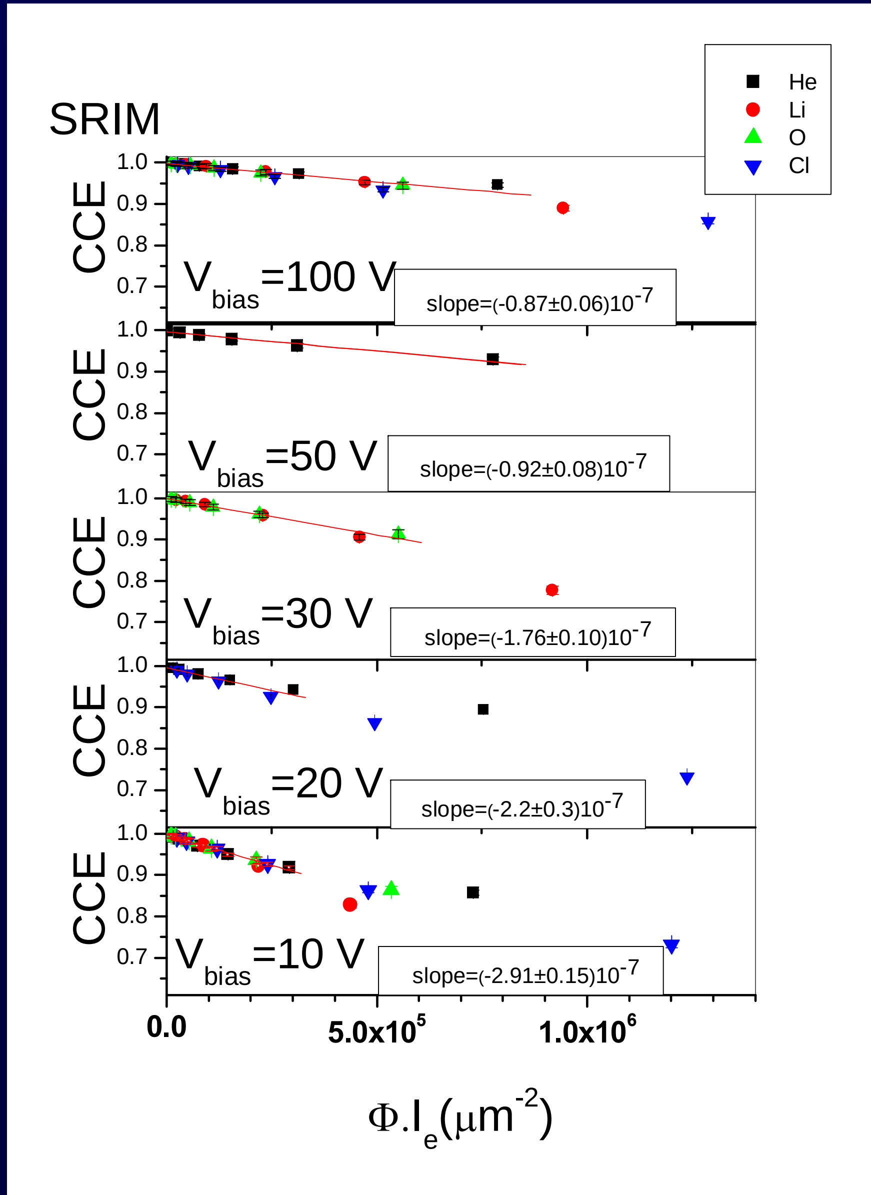
$$K^* = \frac{k_e \cdot \sigma_e \cdot v_{th}}{v_e} = (1.09 \pm 0.02) \cdot 10^{-15}\ \mathrm{cm}^2.$$

$k_e \approx 0.2$

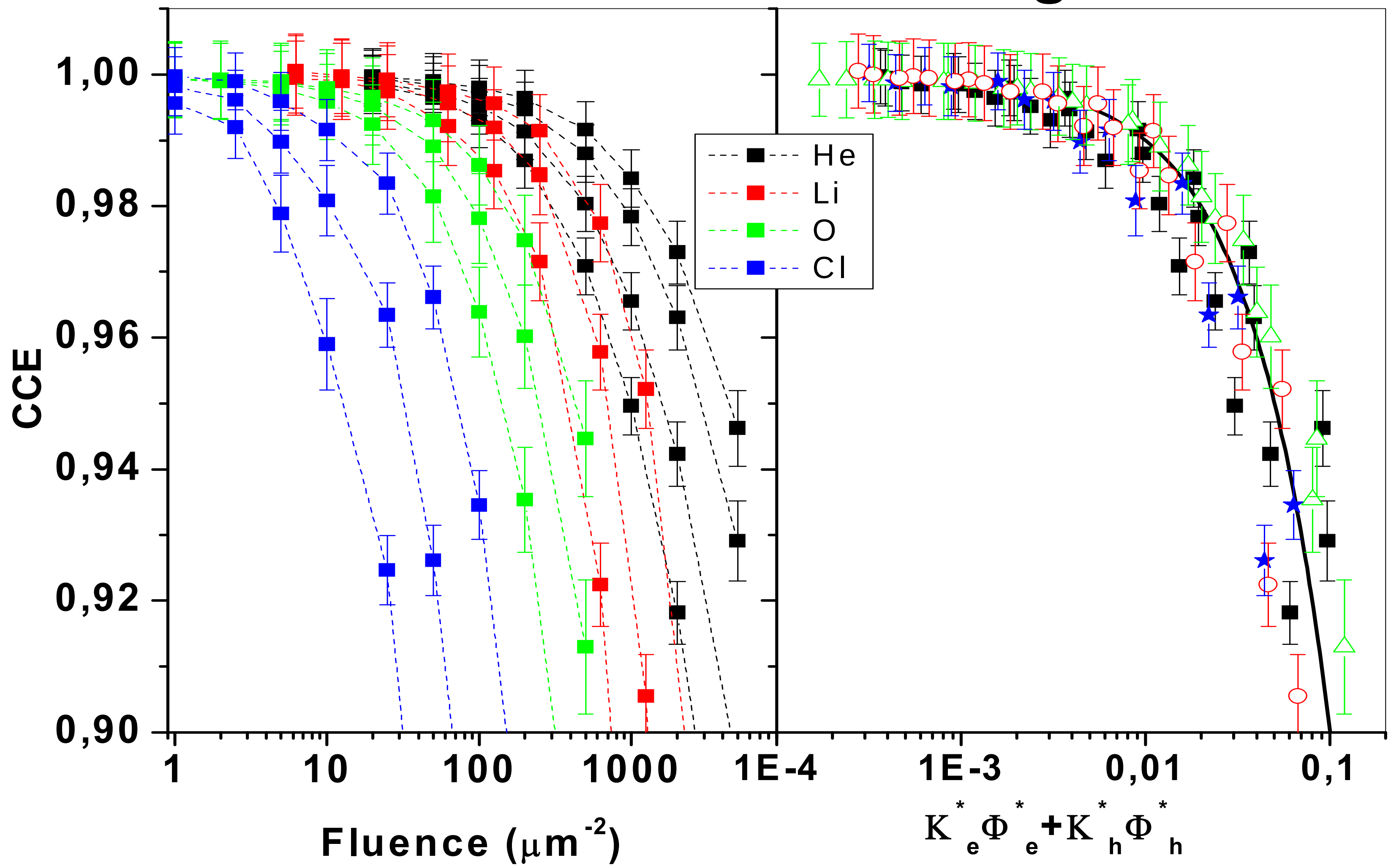
i.e. 5 vacancy to generate an electrically stable trap in low doped n-type silicon

The K* value is independent from the type and energy of the damaging and probing ions and is attributable only to the intrinsic radiation hardness of the material


He
Li
O
Cl
CCE
V_{bias}=100 V
V_{bias}=50 V
V_{bias}=30 V
V_{bias}=20 V
V_{bias}=10 V
0
1x10³
2x10³
3x10³
4x10³
5x10³
Φ(μm⁻²)


SRIM
He
Li
O
Cl
CCE
V_{bias}=100 V
slope=(-0.87±0.06)10⁻⁷
V_{bias}=50 V
slope=(-0.92±0.08)10⁻⁷
V_{bias}=30 V
slope=(-1.76±0.10)10⁻⁷
V_{bias}=20 V
slope=(-2.2±0.3)10⁻⁷
V_{bias}=10 V
slope=(-2.91±0.15)10⁻⁷
0.0
5.0x10⁵
1.0x10⁶
Φ.Iₑ(μm⁻²)

At different bias voltages



In the low damage regime

The degradation of the CCE of a semiconductor detector due to the damage induced by ions of different mass and energy can be interpreted on the basis of a simplified theory of the IBIC technique.

$$CCE(\Phi) \equiv 1 - K_e^* \cdot \Phi_e^*$$

Effective fluence

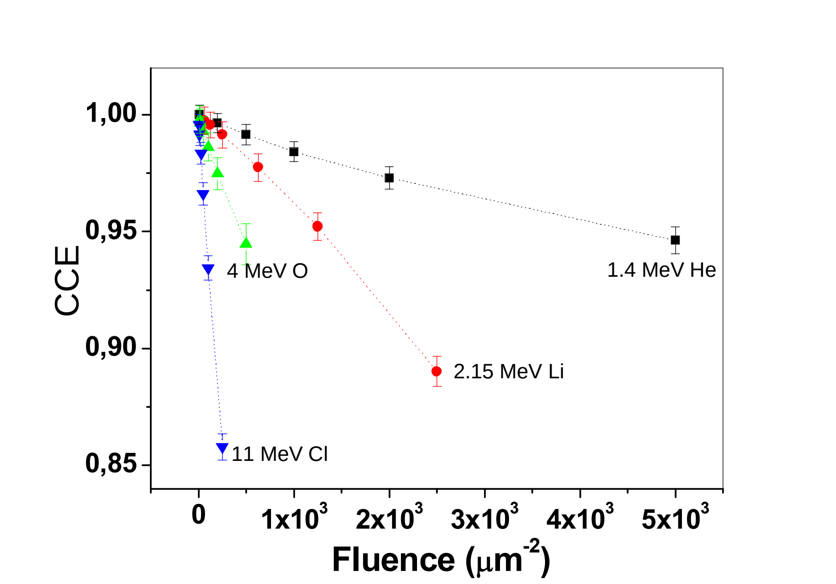
$$\Phi^* = \Phi \cdot \left\{ \frac{1}{d} \cdot \frac{1}{E_P} \int_0^{R_P} dx \frac{dE_P}{dx} \cdot \left[\int_x^d dz \left[V(z) \cdot (d-z) \right] \right] \right\}$$

can be numerically calculated from the vacancy and ionization profiles extracted from the SRIM code.

Effective damage factor

$$K^* = \frac{k_e \cdot \sigma_e \cdot v_{th}}{v_e} = (1.09 \pm 0.02) \cdot 10^{-15}\ cm^2.$$

the effective damage factor K* is the slope of the CCE degradation as function of Φ* is proportional to the fraction of the electrically active trap per vacancy



K* can be considered an index that would reliably rank the relative radiation hardness of semiconductors in order to optimize the selection procedure for devices working in high radiation environment.

Effective damage factor

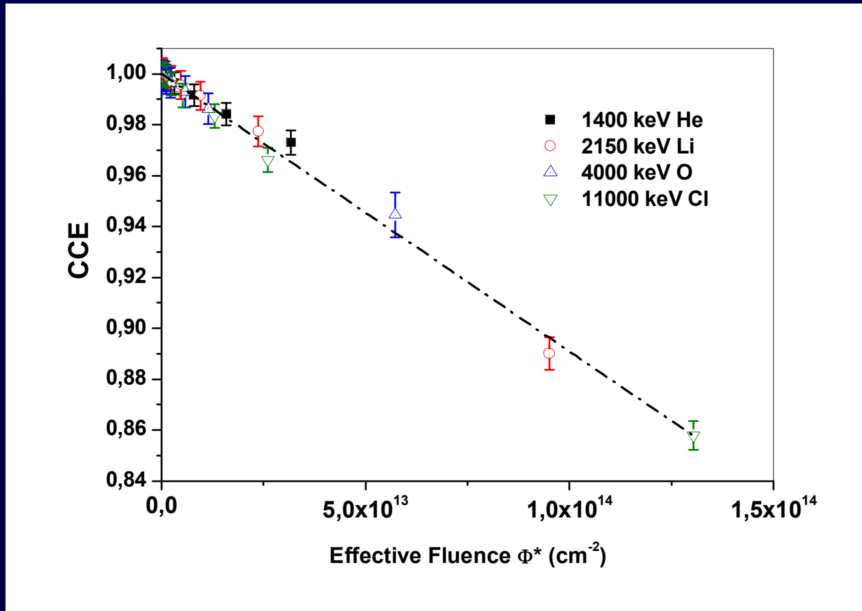
$$K^* = \frac{k_e \cdot \sigma_e \cdot v_{th}}{v_e} = (1.09 \pm 0.02) \cdot 10^{-15}\ cm^2.$$

σ : measured from DLTS

vth: thermal velocity

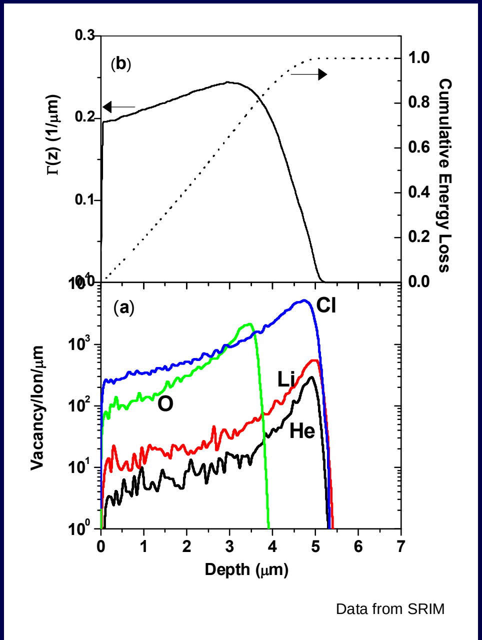
ve=: electron average velocity

ke: average number of trap/vacancy

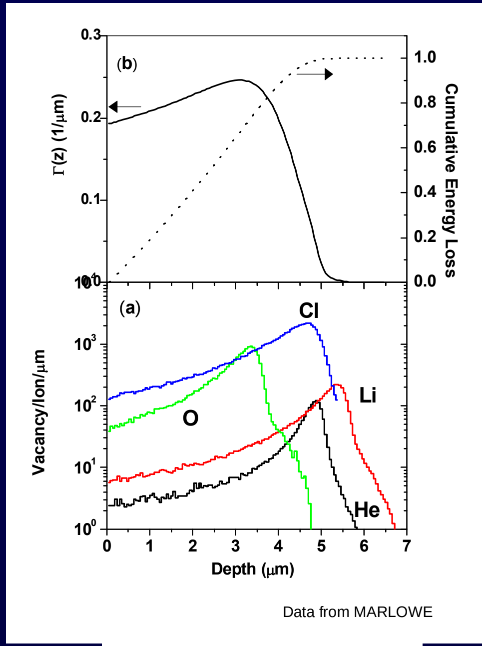


Approach more efficient to condense the CCE degradation data into a single curve than the phenomenological displacement damage dose analysis;

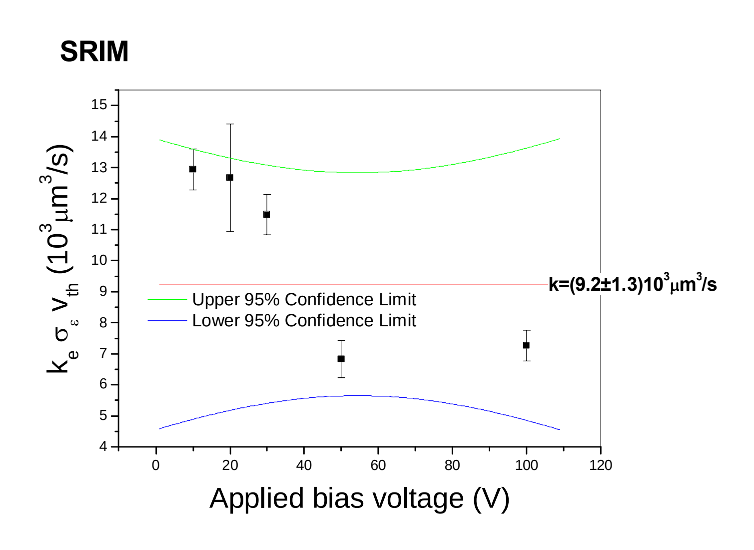
NIEL is valid only in the case of constant vacancy profile.

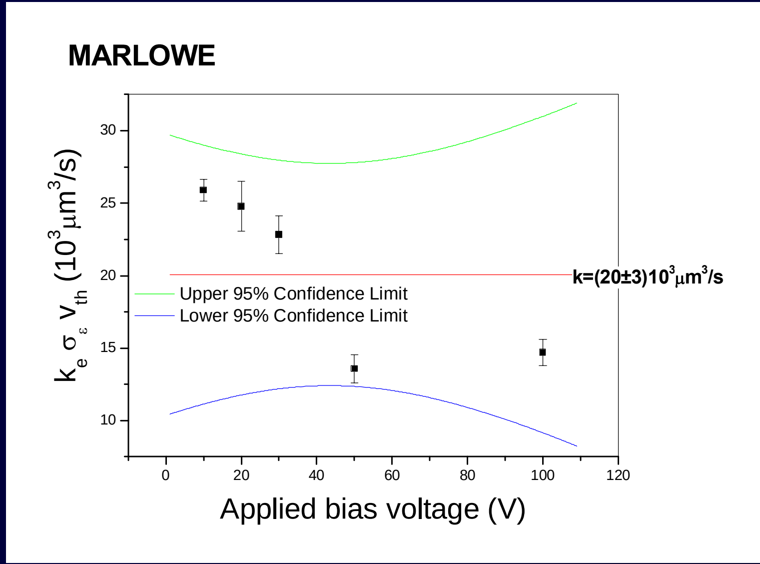


SRIM



MARLOWE





IAEA Coordinate Research Programme (CRP) F11016 (2011-2015)
"Utilization of ion accelerators for studying and modeling of radiation induced defects in semiconductors and insulators"

Overall Objective:

Use of ion accelerators for improved understanding of how radiation induced defects influence the electronic properties of semiconductor/insulator materials, leading to better understanding of how they degrade or improve the performances of devices in extreme and harsh radiation environments.

Specific Research Objective:

Deeper theoretical knowledge and experimental data on defects created by light and heavy ions; in terms of their type, density and effect on fundamental electronic properties of semiconductors and insulators.

Expected Research Outputs:

Definition of an experimental protocol to determine the key parameters for the characterization of the effects of radiation damage on semiconductor materials and devices.

Refined theoretical models for defect generation and for modelling their effect on electronic properties.

Low Level of damage

Vacancy profille
(from SRIM, MARLOWE; PAS)

Shockley-Read-Hall
Recombination/trapping
model

Electrostatics of the
device (TCAD)

Trap cross section

Shockley-Ramo-Gunn Theorem
Adjoint equation formalism
Finite element method
Monte Carlo method
Semi-analytical approach in simple cases

Trap/vacancy ratio
Radiation hardness